



The Abdus Salam
International Centre for Theoretical Physics



SMR/1758-19

**"Workshop on Ion Beam Studies of Nanomaterials:
Synthesis, Modification and Characterization"**

26 June - 1 July 2006

**Quantum Wells/Dots & Nanowires
for Optoelectronic Device Applications**

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Quantum Wells/Dots and Nanowires for Optoelectronic Device Applications

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The Australian National University, Canberra, Australia

The Group



**Few people are missing
(M. Buda, Y. Kim, Q. Gao, J. Wong-Leung, H. Hattori)**

Overview

- **Introduction**
- **Growth of Quantum Dots by Metal Organic Chemical Vapour Deposition (MOCVD)**
- **Towards Quantum Well/Dot Photonic Integrated Circuits**
 - **Intermixing (QW/QD) by ion implantation**
 - **Quantum Well/Dot Lasers**
 - **Quantum Well/Dot Infrared Photodetectors (QDIPs)**
- **Carrier lifetime Modification by Ion Implantation for ultra-fast detectors and THz emitters**
- **Nanowires**
- **Summary**

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Source: Osram, Corning, Sony, Jim Harris, Joe Campbell

Optoelectronics



Compound Semiconductors – GaAs, GaP, GaN, AlAs, InAs, InP, InN, AlN, ZnO

LEDs for Lighting Applications

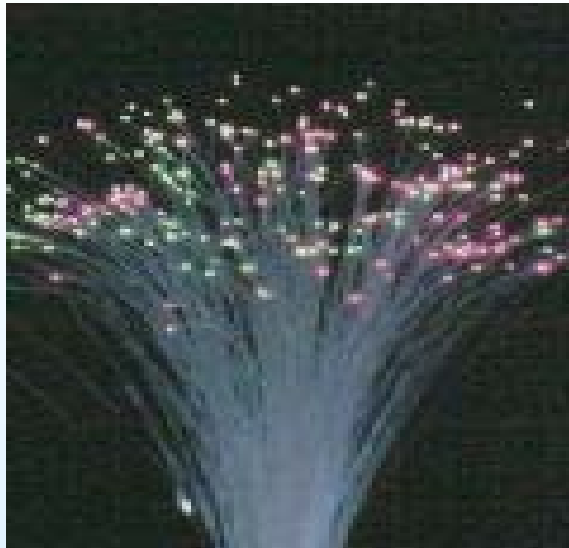


J. Pankove
I. Akasaki
S. Nakamura



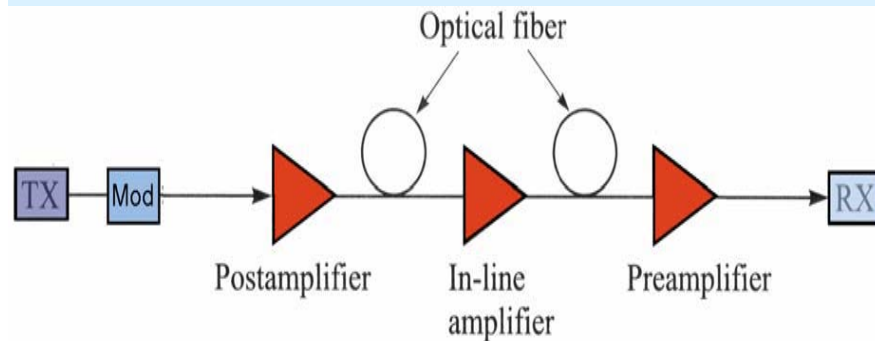
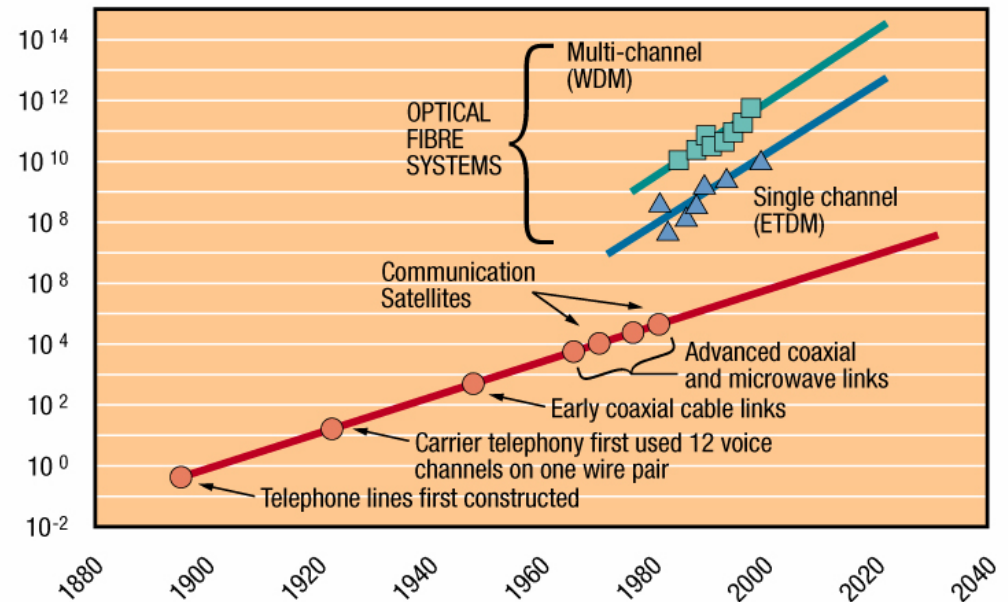
II	III	IV	V	VI
Be	B	C	N	O
Mg	Al	Si	P	S
Zn	Ga	Ge	As	Se
Cd	In	Sn	Sb	Te
Hg	Tl	Pb	Bi	Po

Optical Fiber Communications



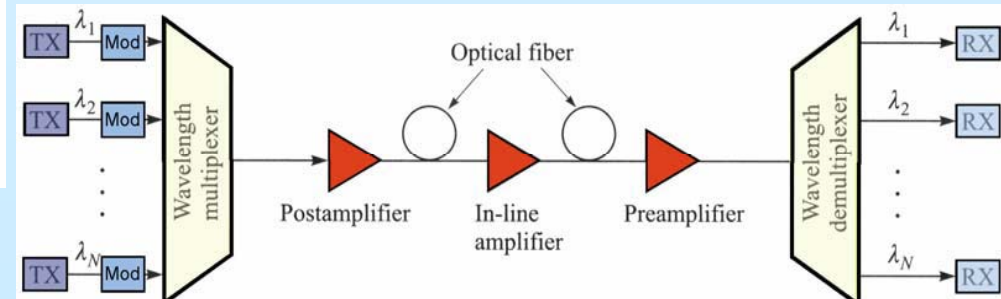
**Lasers, Modulators, Photodetectors
1310 and 1550 nm**

Communications capacity - Growth
RELATIVE INFORMATION CAPACITY, BITS/S



Single Channel Optical Link

Wavelength Division Multiplexing

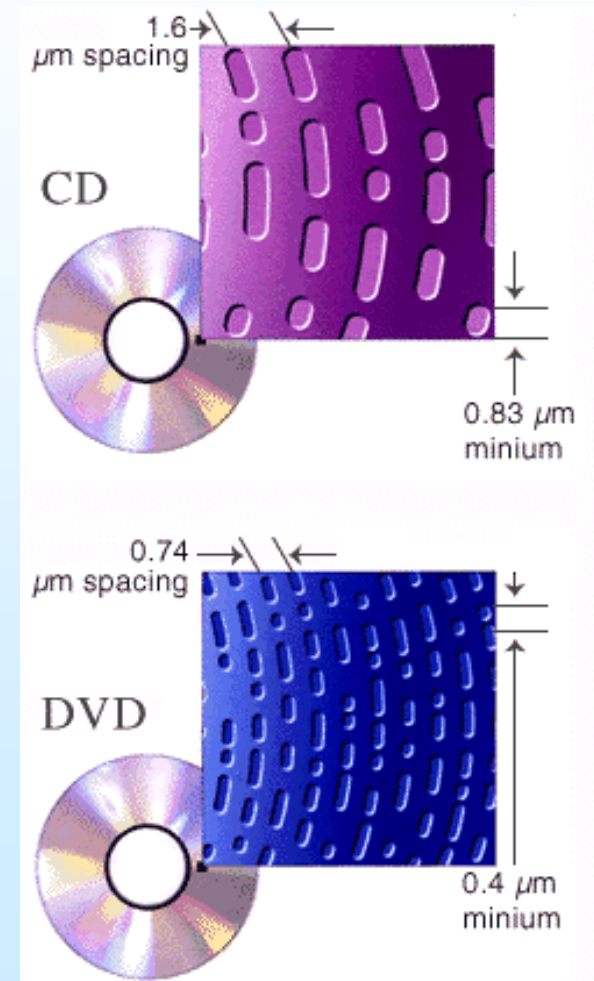


High Density Data Storage / Entertainment

CDs (780 nm - Infrared)

DVDs (650 nm - Red)

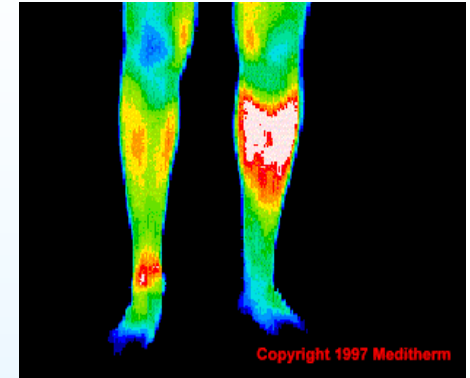
HD-DVDs (405 nm- Violet)



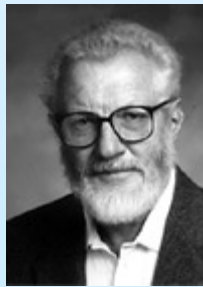
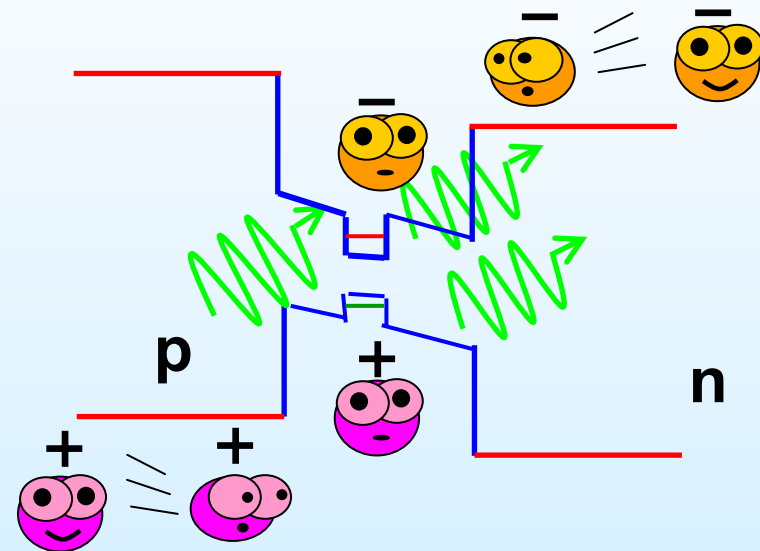
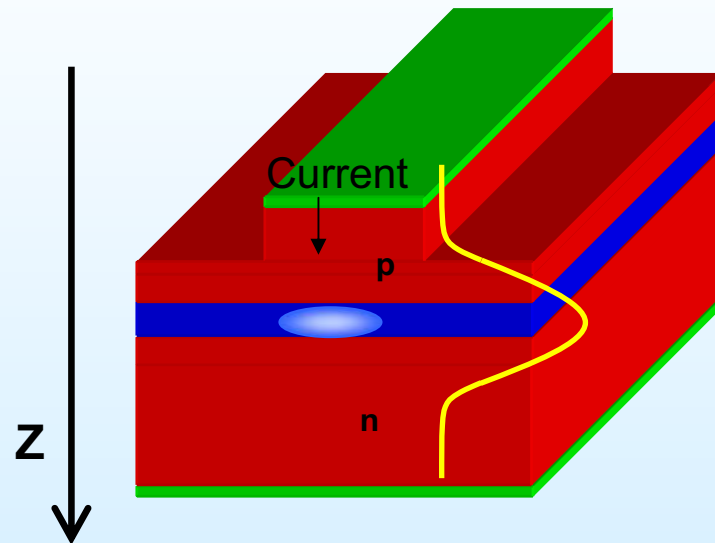
Infra-red Photodetectors

Long-wavelength infrared radiation detection (2-30 μ m):

- **Applications**
 - Thermal imaging, night vision, space ranging, thermal analysis, atmospheric sensing
- **Type of semiconductor detectors**
 - Intrinsic: HgCdTe, InSb, PbS, PbSe
 - Extrinsic: Si:In, Si:Ga, Si:As
 - Intersubband transition (III-V): QWIPs
- **Advantages of QWIPs (and QDIPs)**
 - Mature epitaxial and fabrication technologies
 - High degree of uniformity
 - Easy to fabricate large arrays and monolithic integration
 - Lower cost

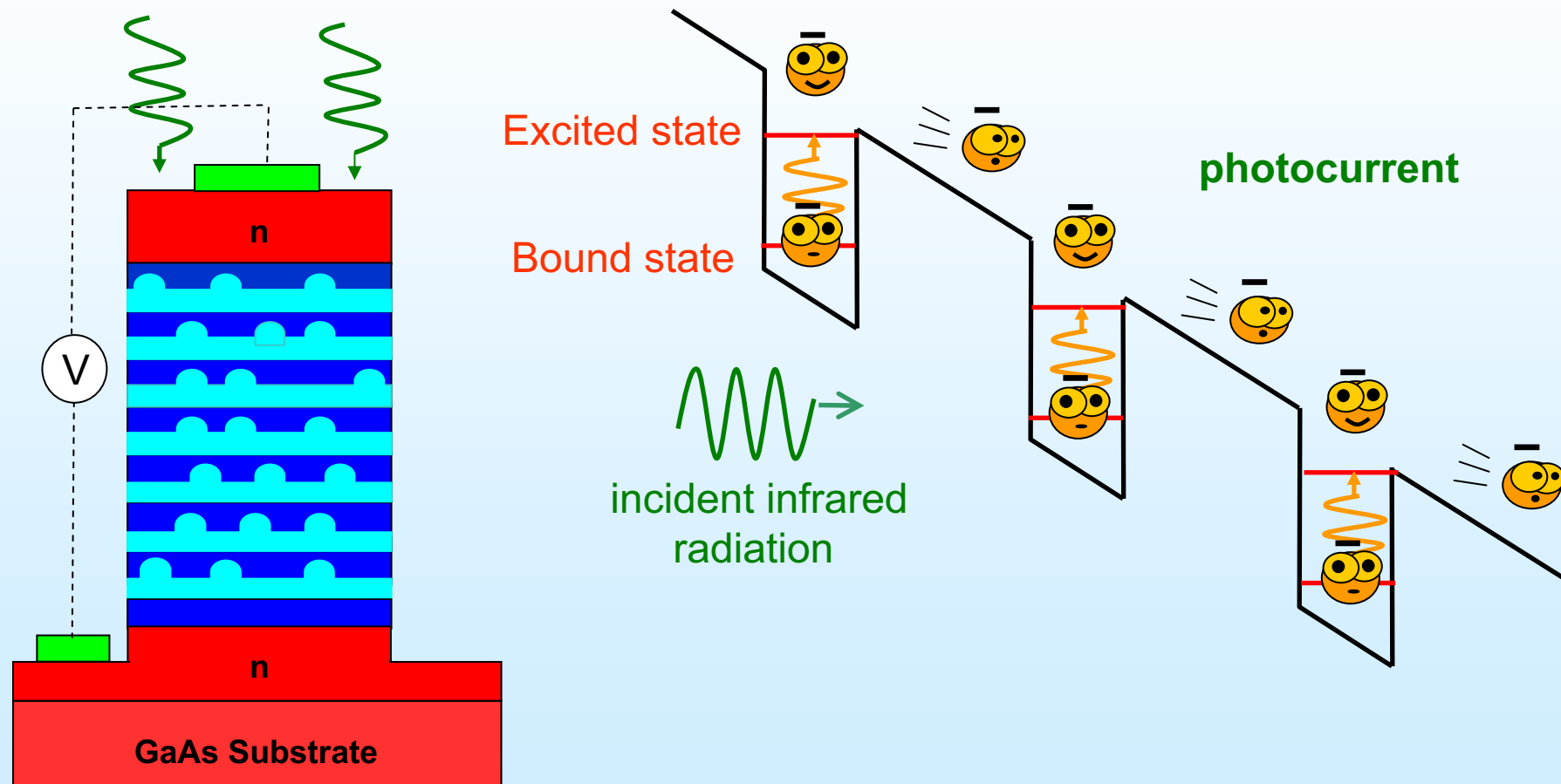


How a Semiconductor Laser Works?

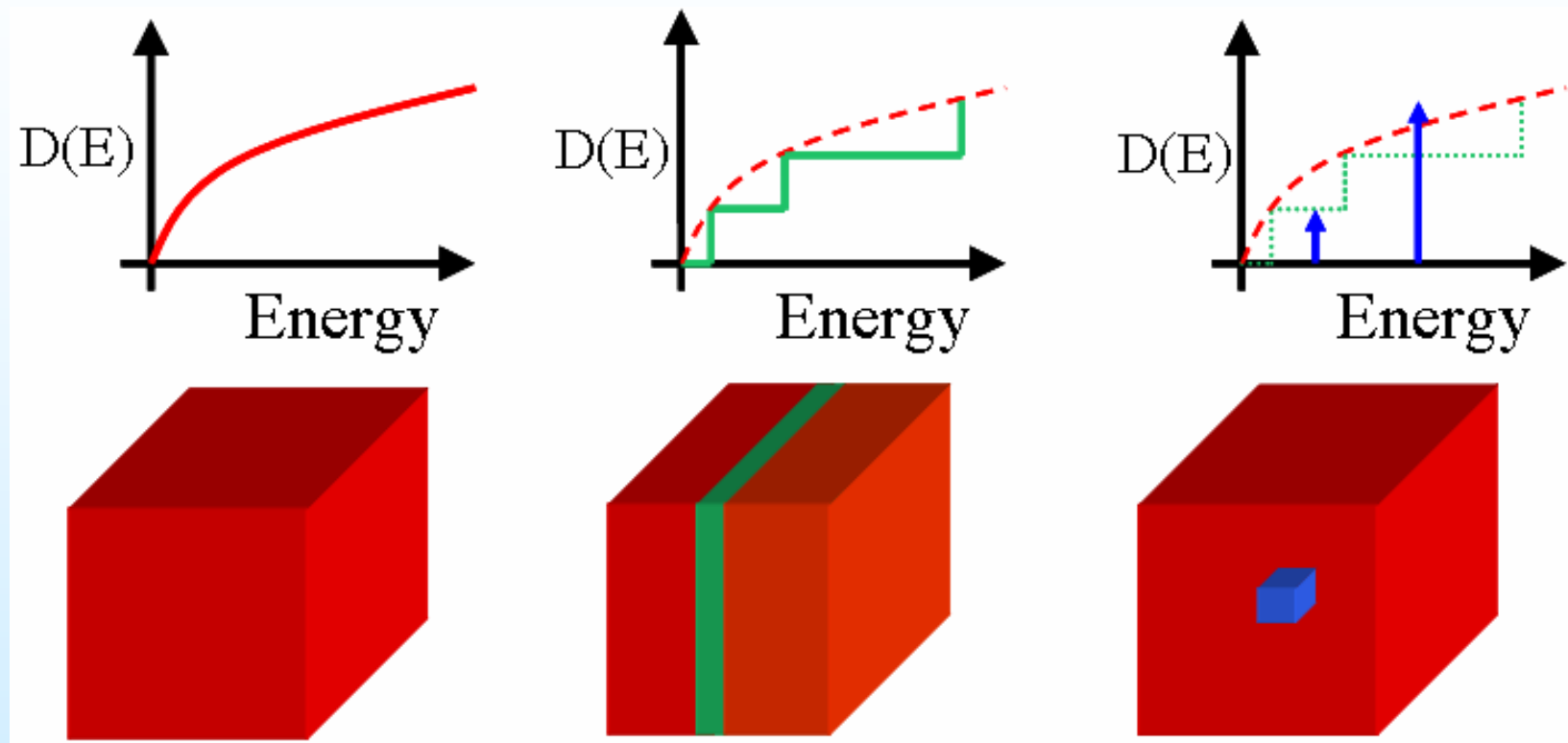


**Zhores Alferov,
Herbert Kroemer, 1963
2000 Nobel Prize for Physics**

How a QW/QD Infrared Detector (QDIP) Works?



Why Quantum Dots?

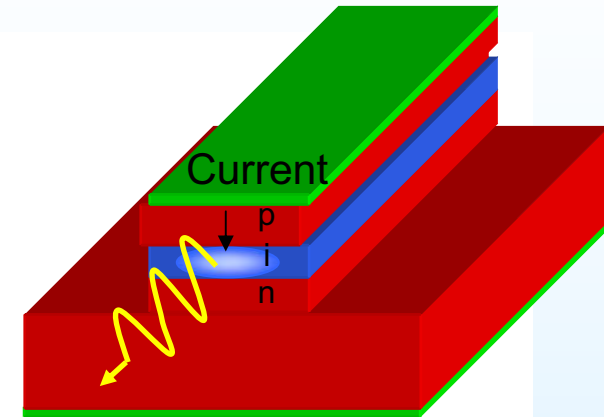


**3D Carrier Confinement in QDs Leads to
Atom-Like Density of States**

QD Optoelectronic Devices

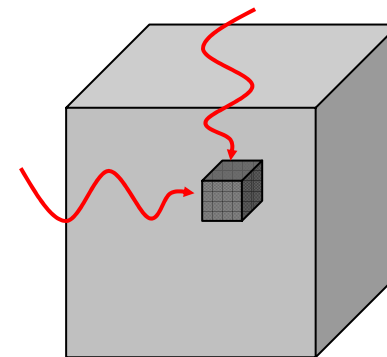
- **Lasers**

- reduced threshold current
- increased differential gain (gain per injected electron)
- less temperature sensitive threshold current and emission wavelength
- longer wavelength VCSELs (1.3 and 1.55 μm)



- **Infrared Photodetectors (Inter sub-band)**

- normal incidence operation
- higher detector responsivity
- higher operating temperature



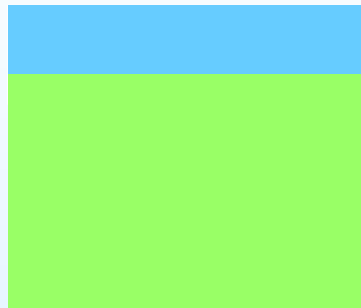
QDIPs: Normal
incidence detection

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Self-assembled Growths of Quantum Dots

Frank-van der Merwe

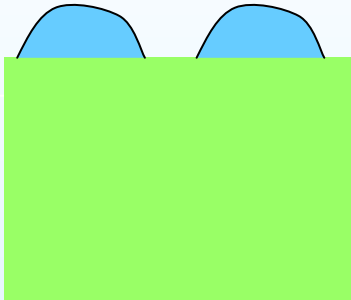


Layer by Layer

**Lattice
matched
systems**

**(AlGaAs on
GaAs)**

Volmer-Weber

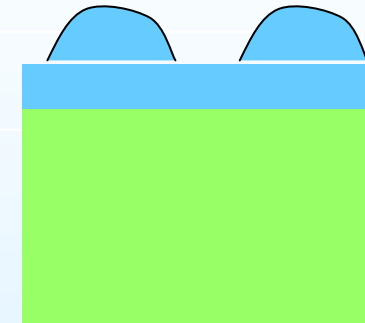


Direct Island

**Large lattice
mismatch
Very high interfacial
energy**

(GaN on Sapphire)

Stranski-Krastanow



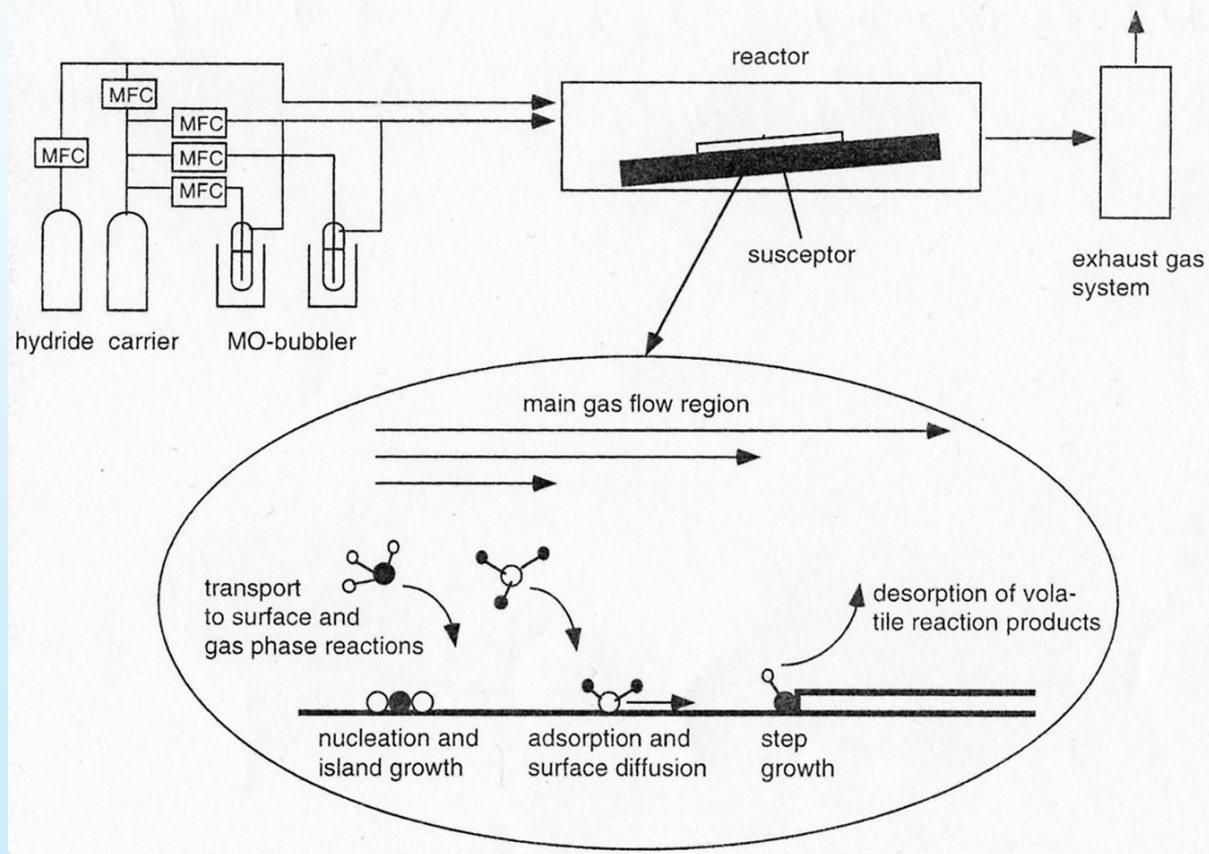
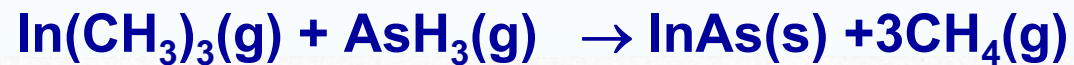
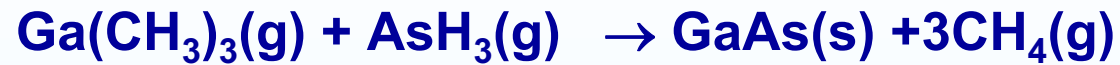
**Layer by layer,
then Island
nucleation**

**Dissimilar lattice
spacing, low
interfacial energy**

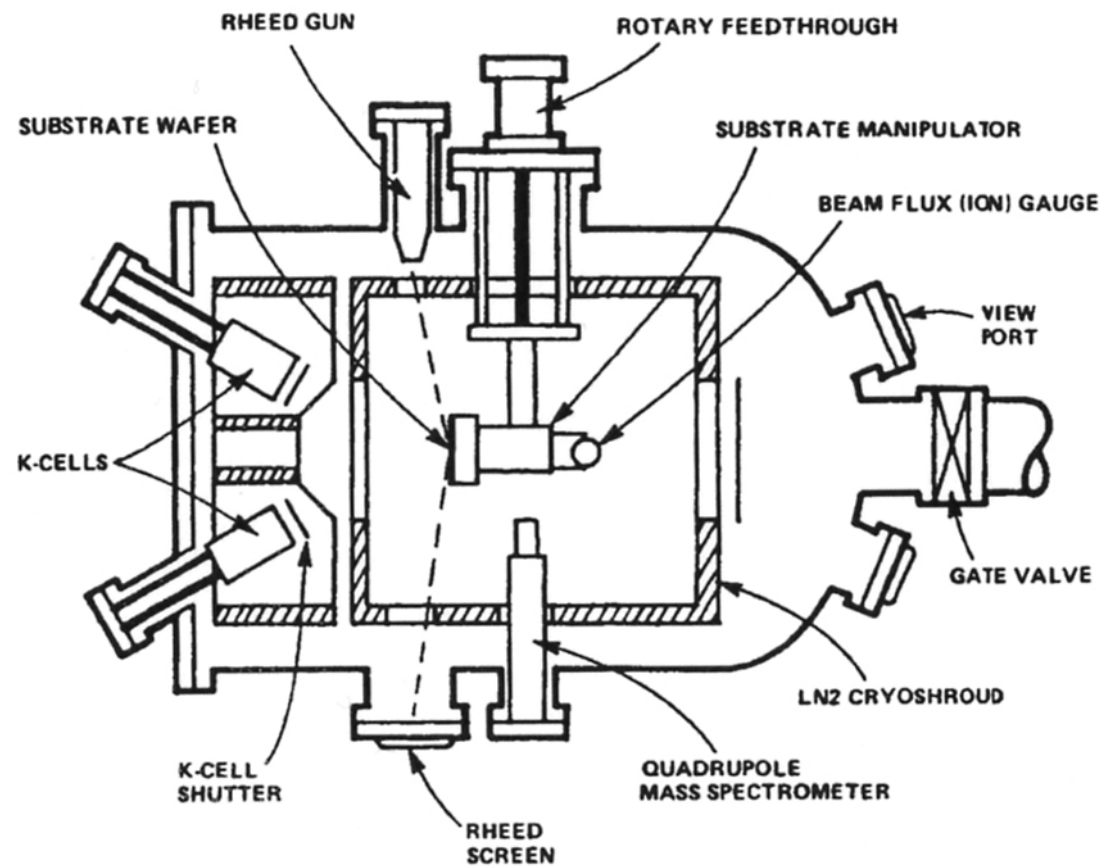
**(In(Ga)As on
GaAs)**



Metal Organic Chemical Vapour Deposition (MOCVD)

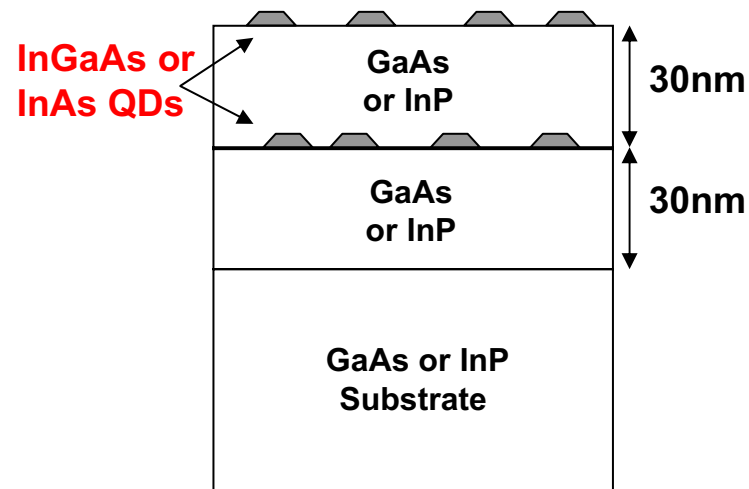


Molecular Beam Epitaxy (MBE)



MOCVD - high T growth and lack of in-situ monitoring

- Aixtron 200/4 MOCVD reactor
- TMGa, TMAI, TMIIn, AsH₃, PH₃ (Dissociation of gases)
- In_{0.5}Ga_{0.5}As, InAs Quantum dots
- Dot growth ~500-550°C, Other layers at 600-650°C
- AFM (surface dots) and PL (buried dots)



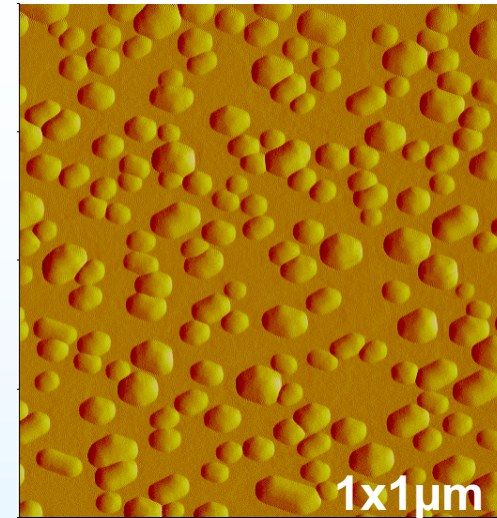
Growth Parameters

Amount of Material (**Size and Density**)

Growth Temperature (**Adatom Mobility, Size & Density**)

Growth Rate (**Size and Density**)

V/III Ratio (**Adatom Mobility, Atomic Hydrogen**)



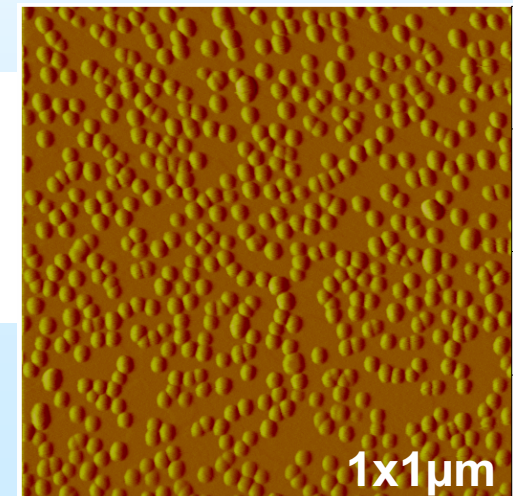
InAs/InP QDs

Desired Properties

High density of smaller coherent islands

Good size uniformity

Minimize / avoid formation of dislocated large islands



InGaAs/GaAs QDs

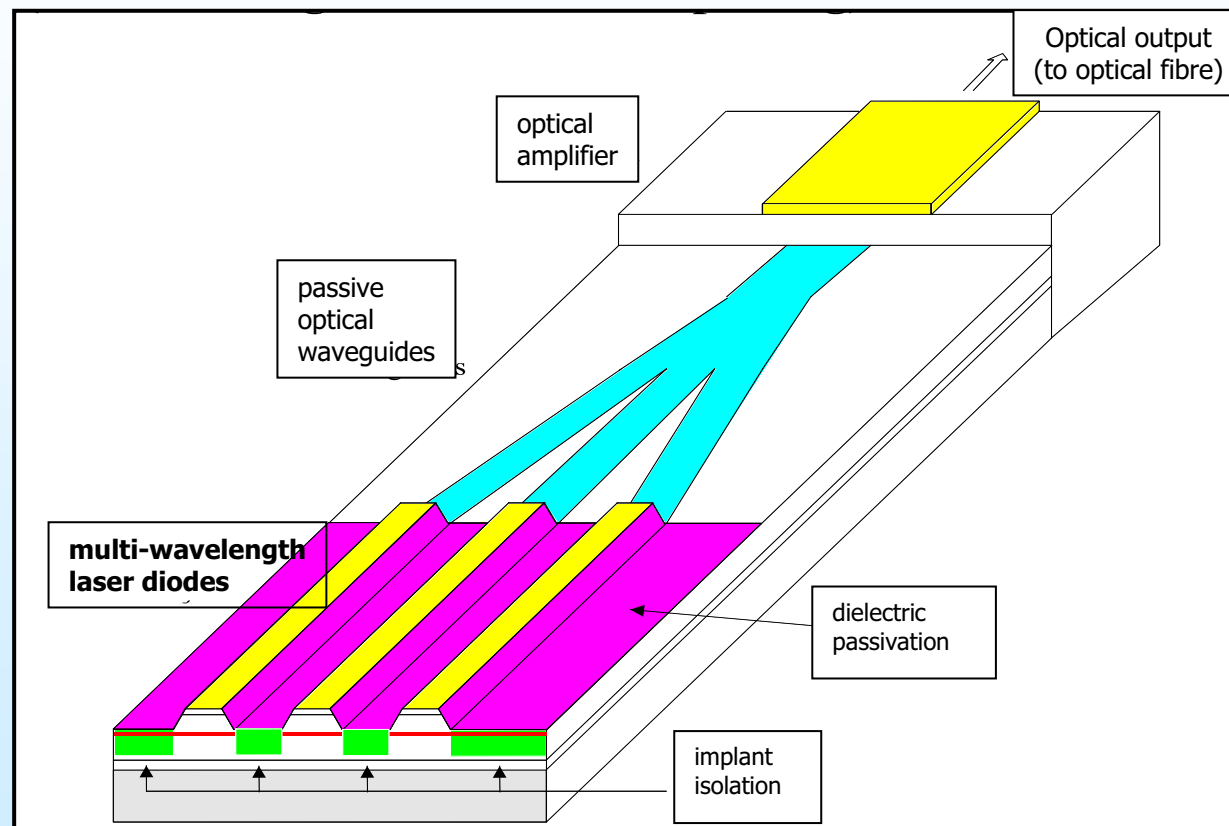
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Photonic Integrated Circuits / Optoelectronic Integrated Circuits

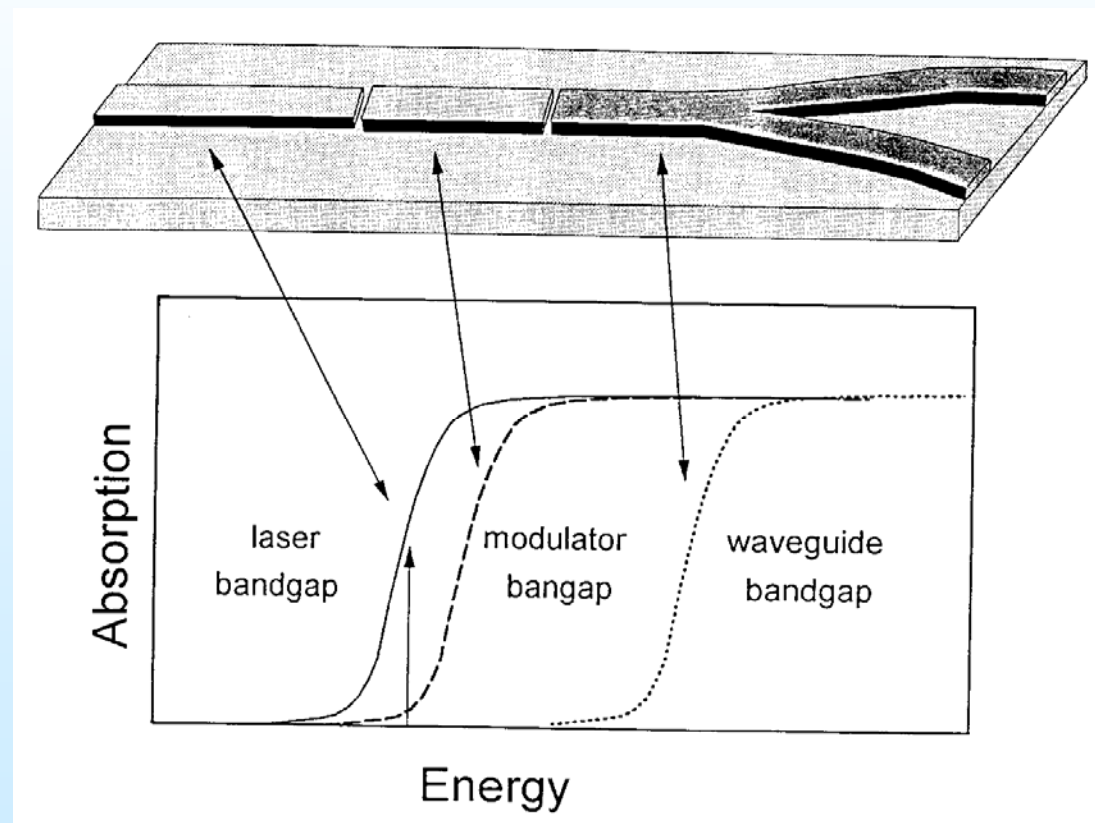
- **Integrated Circuits Show Superior Performance Over Discrete Devices**
- **Multi-functional circuits, e.g. WDM sources**
- **Integrated Transceivers**
- **Low Cost, Packaging**

WDM



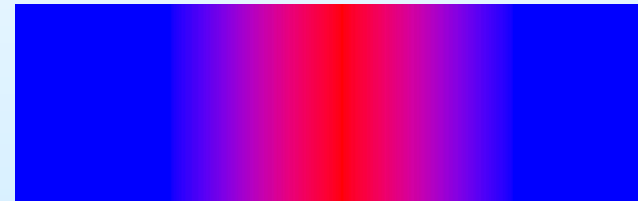
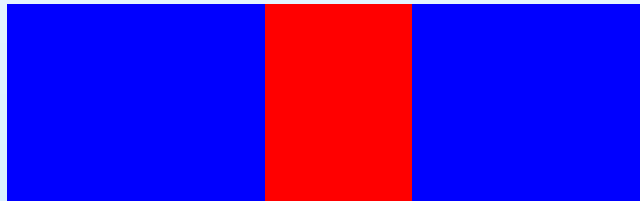
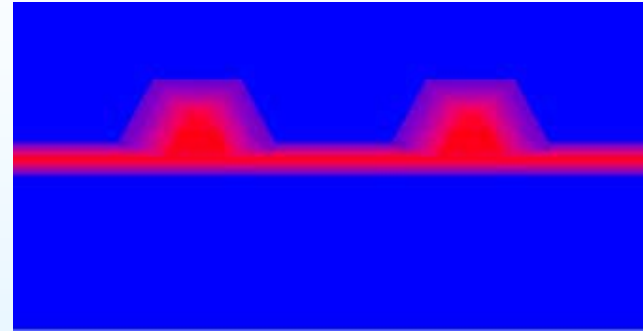
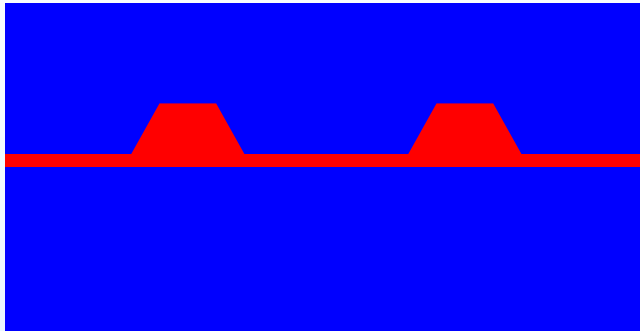
Photonic Integrated Circuits

**Different Bandgaps
on the same chip**



Quantum Well/Dot Intermixing / Selective Area Epitaxy

Quantum Well/Dot Intermixing

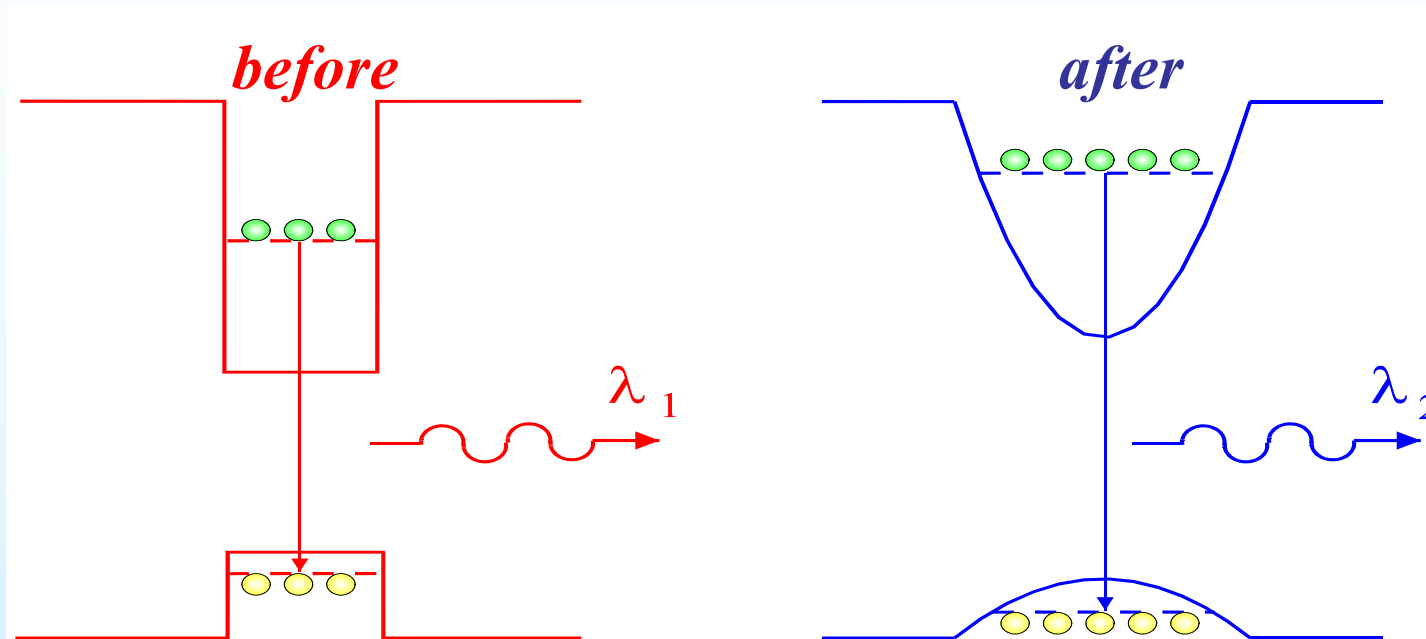


before

after

Non-uniform composition profile

Quantum Well/Dot Intermixing



- Diffusion of In and Ga across interface creates graded region in the case of GaAs/InGaAs Quantum Dots
- Changes Bandgap, refractive index, absorption Coefficient

Methods Widely Used for Quantum Well (Dot) Intermixing

Impurity Induced Disorder, e.g. Zn, Si

Impurity Free Interdiffusion, e.g. SiO_2 , SOG

Ion Implantation Induced Interdiffusion

**Defects introduced by these methods enhance
atomic interdiffusion**

Goals:

**High Selectivity and Low Concentration of Residual
Defects while achieving large band gap differences**

Why Ion Implantation?

Widely used in Microelectronics Industry

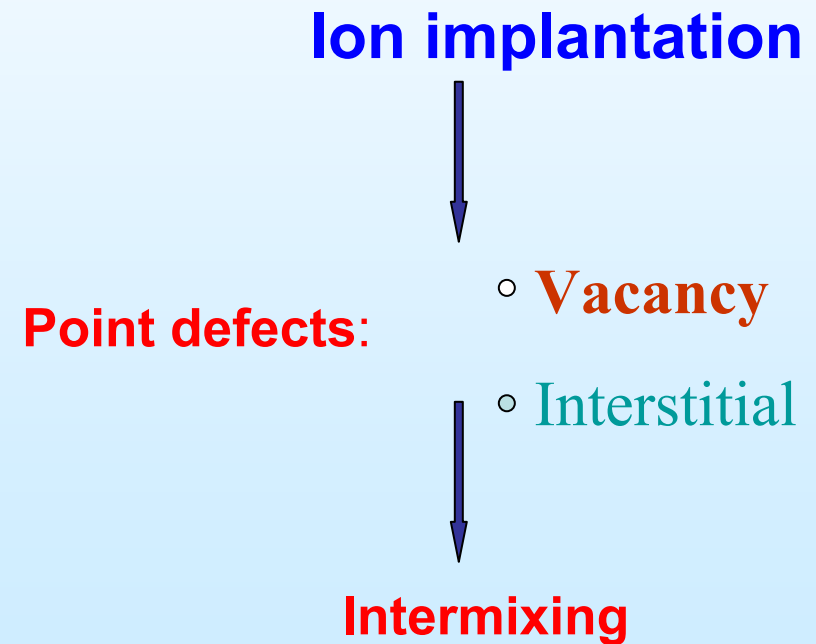
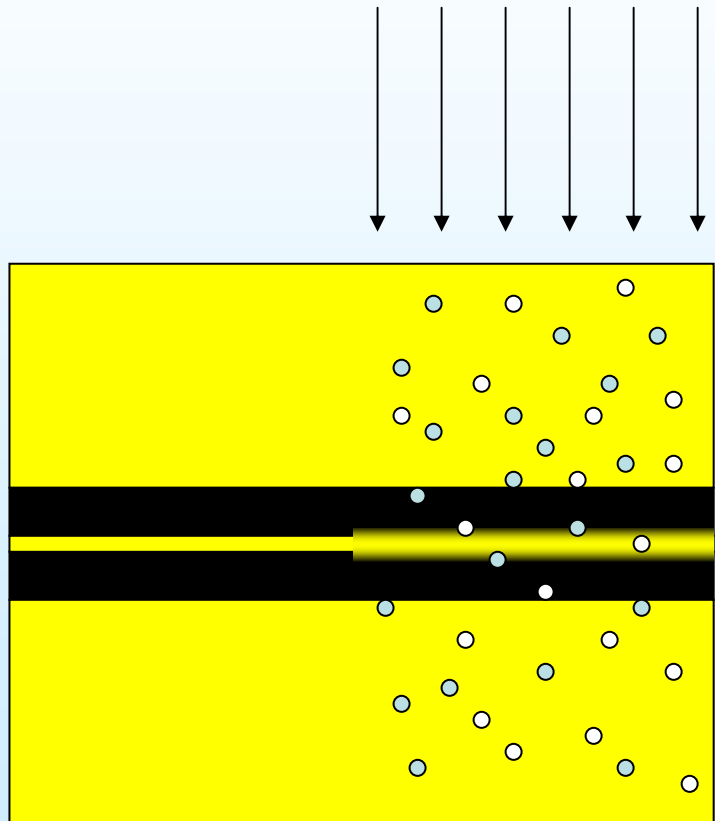
Defect Concentration

- Ion Dose, Ion Mass, Implant Temperature, Dose Rate

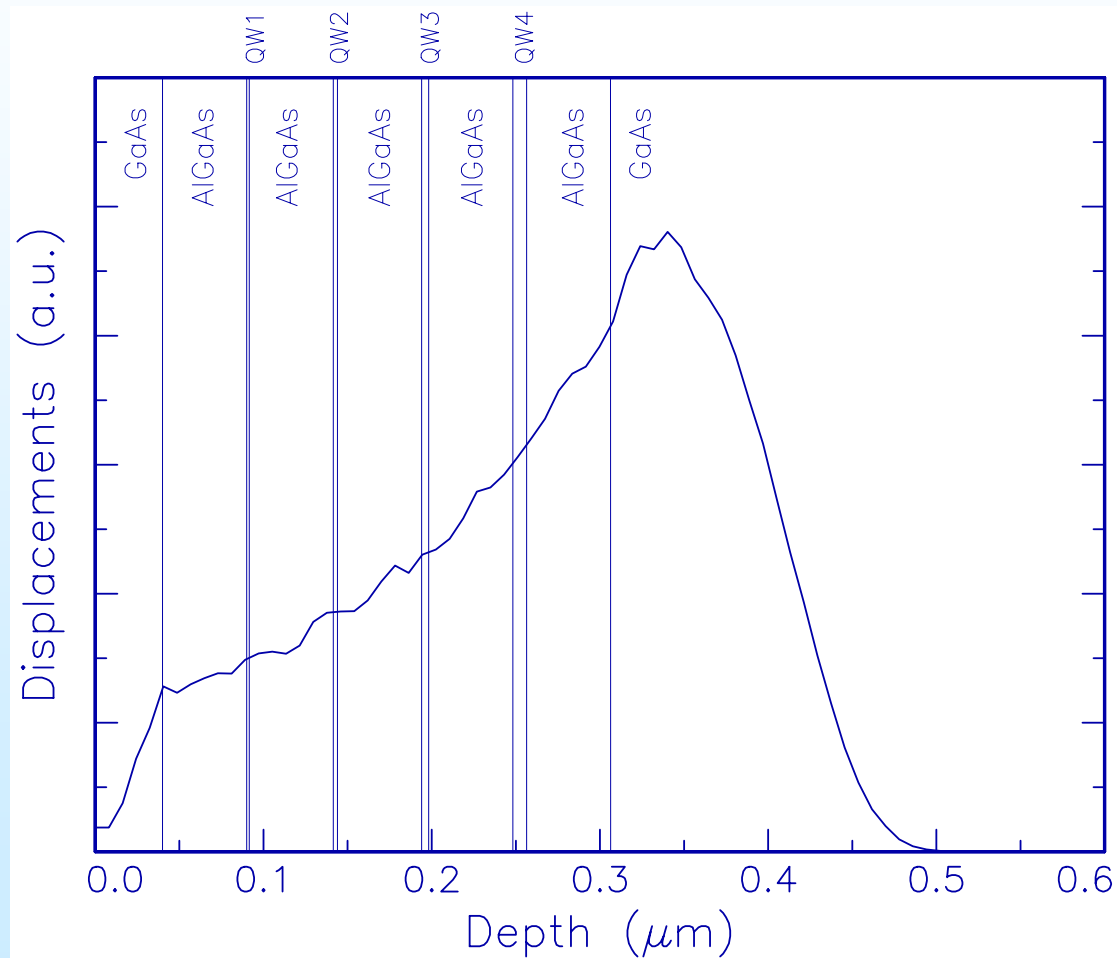
Defect Depth - Ion Energy

Selective Ion Implantation using Masks

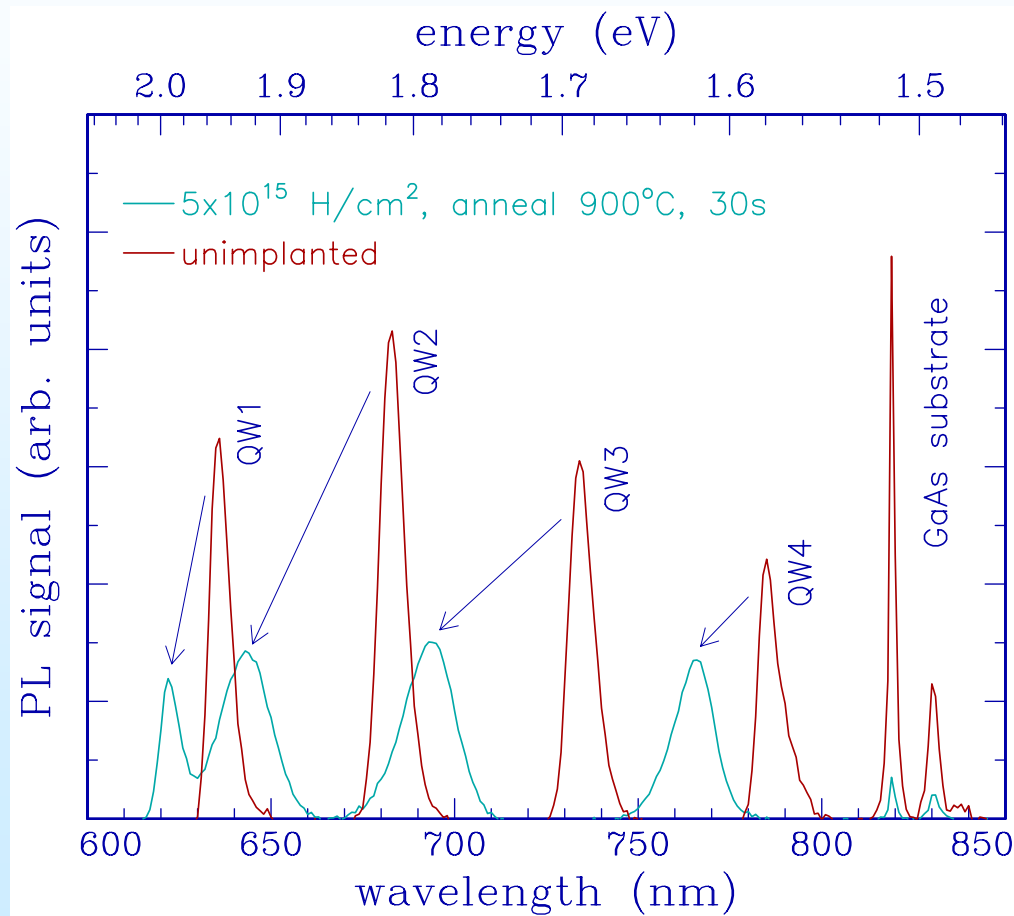
Ion implantation induced quantum well/dot intermixing



Schematic of 4 QW structure (40 keV Proton Defect Profile)



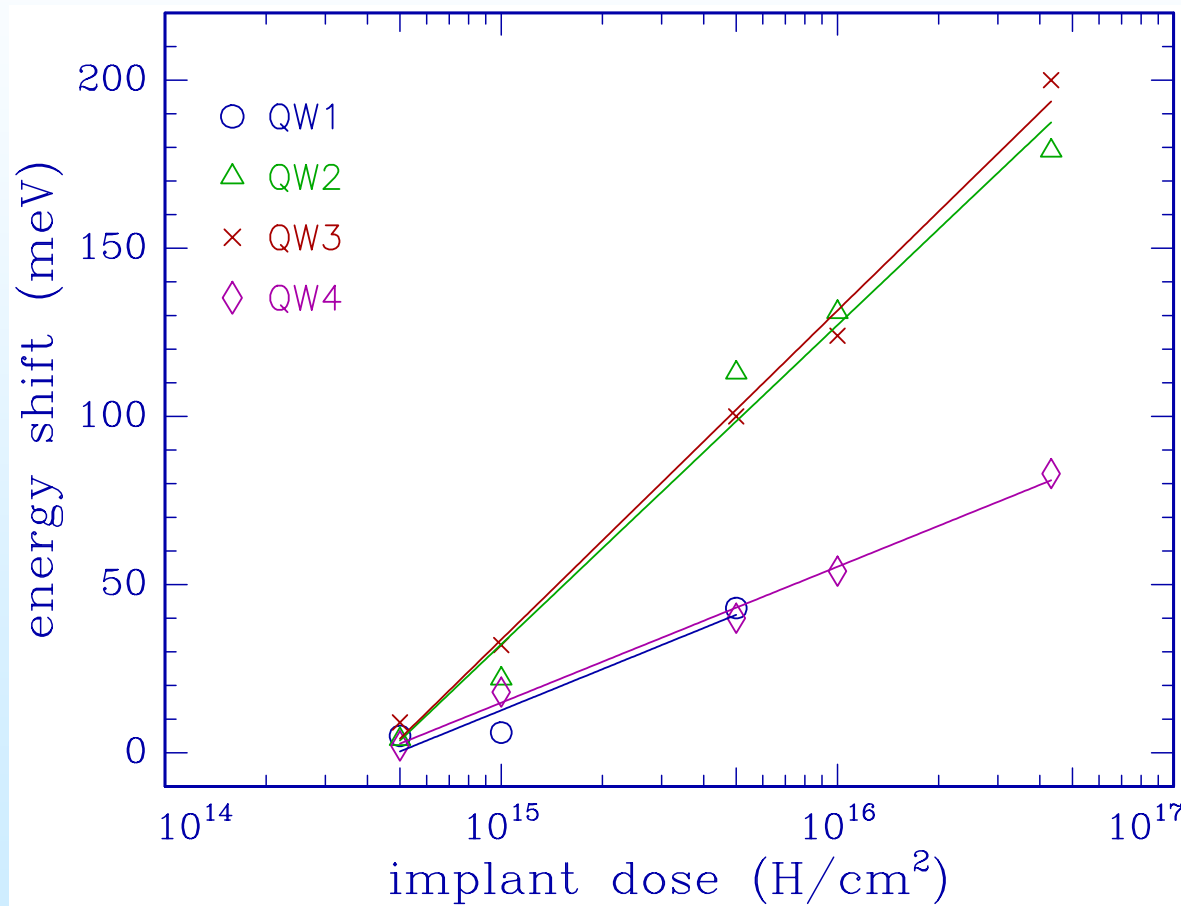
10K Photoluminescence Spectra



**H.H. Tan et.al.,
Appl. Phys. Lett.
68, 2401 (1996).**

Energy Shifts vs. Proton Dose

900°C, 30 sec

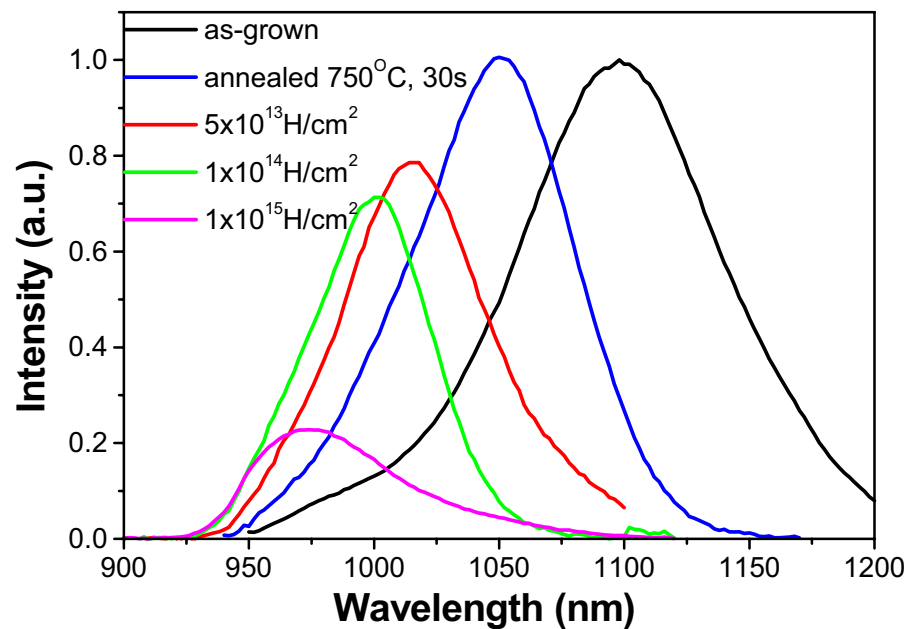


QW1 = 1.4 nm
QW2 = 2.3 nm
QW3 = 4.0 nm
QW4 = 8.5 nm

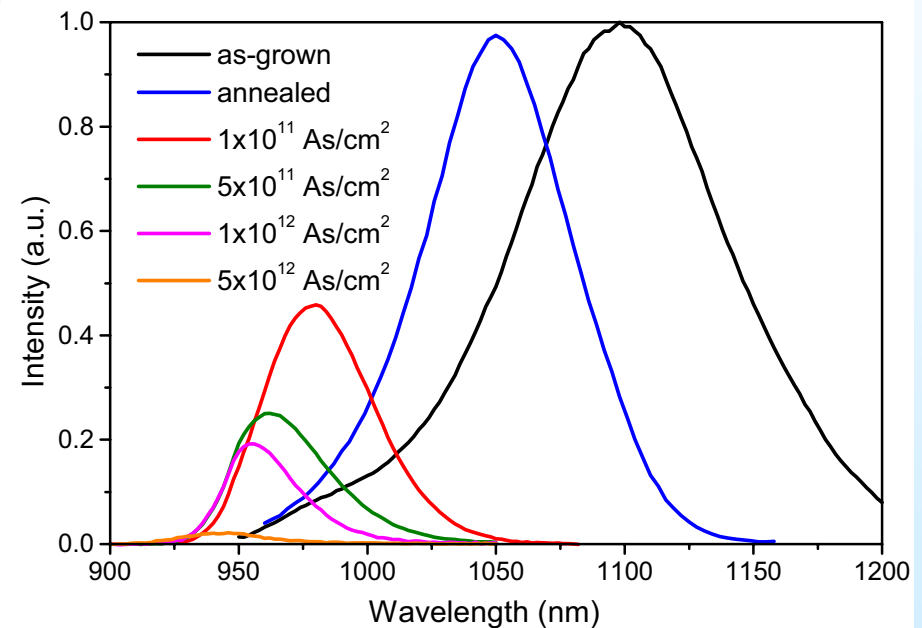
H.H. Tan et.al.,
Appl. Phys. Lett.
68, 2401 (1996).

Implantation Induced InGaAs QD Interdiffusion

Protons



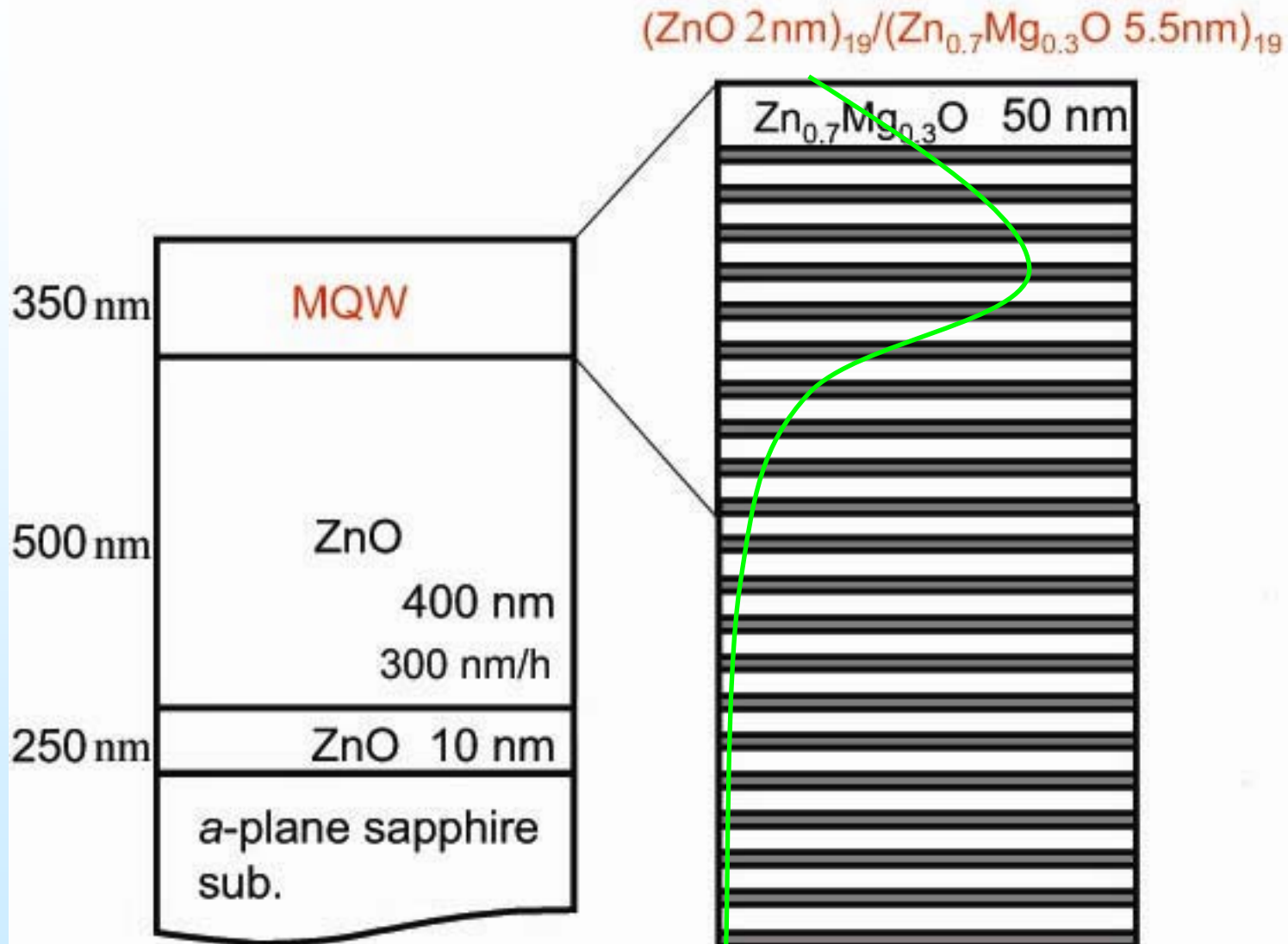
Arsenic Ions



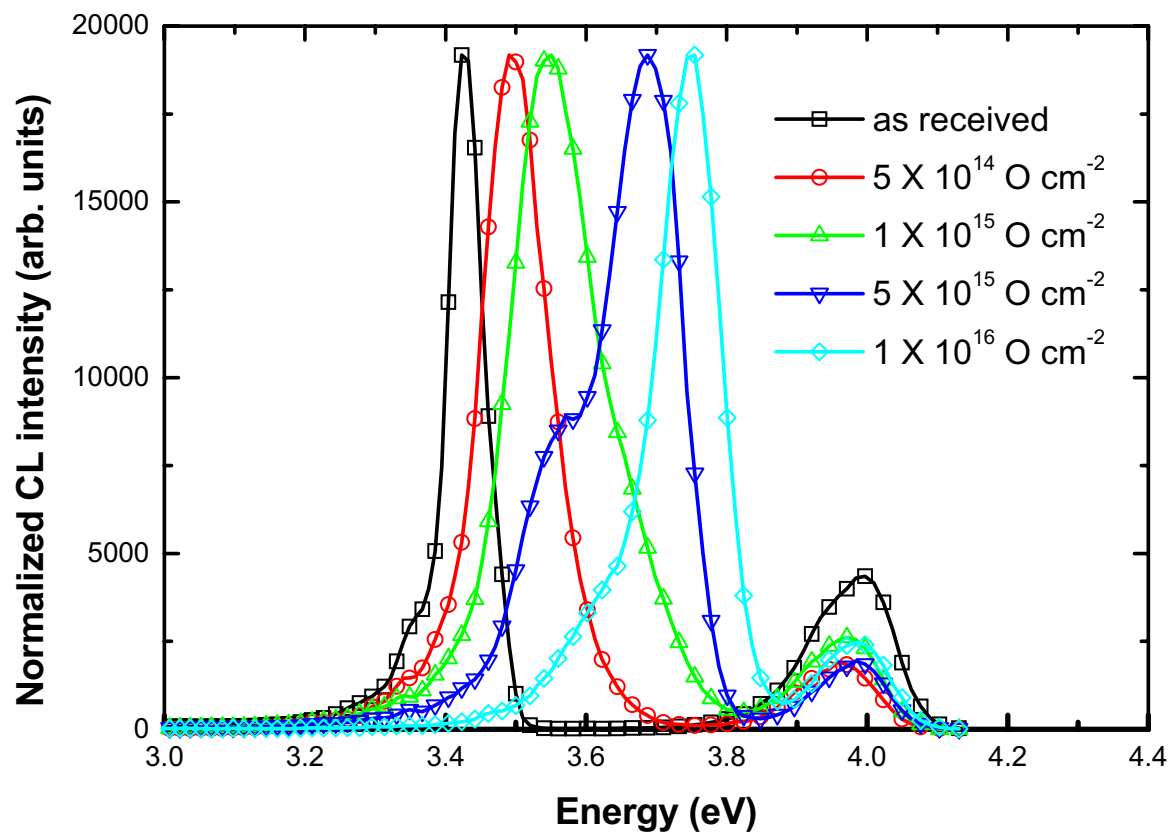
P. Lever et al, Appl. Phys. Lett. 82, 2053 (2003)

Low Dose – 80 keV O → ZnO/Zn_{0.7}Mg_{0.3}O

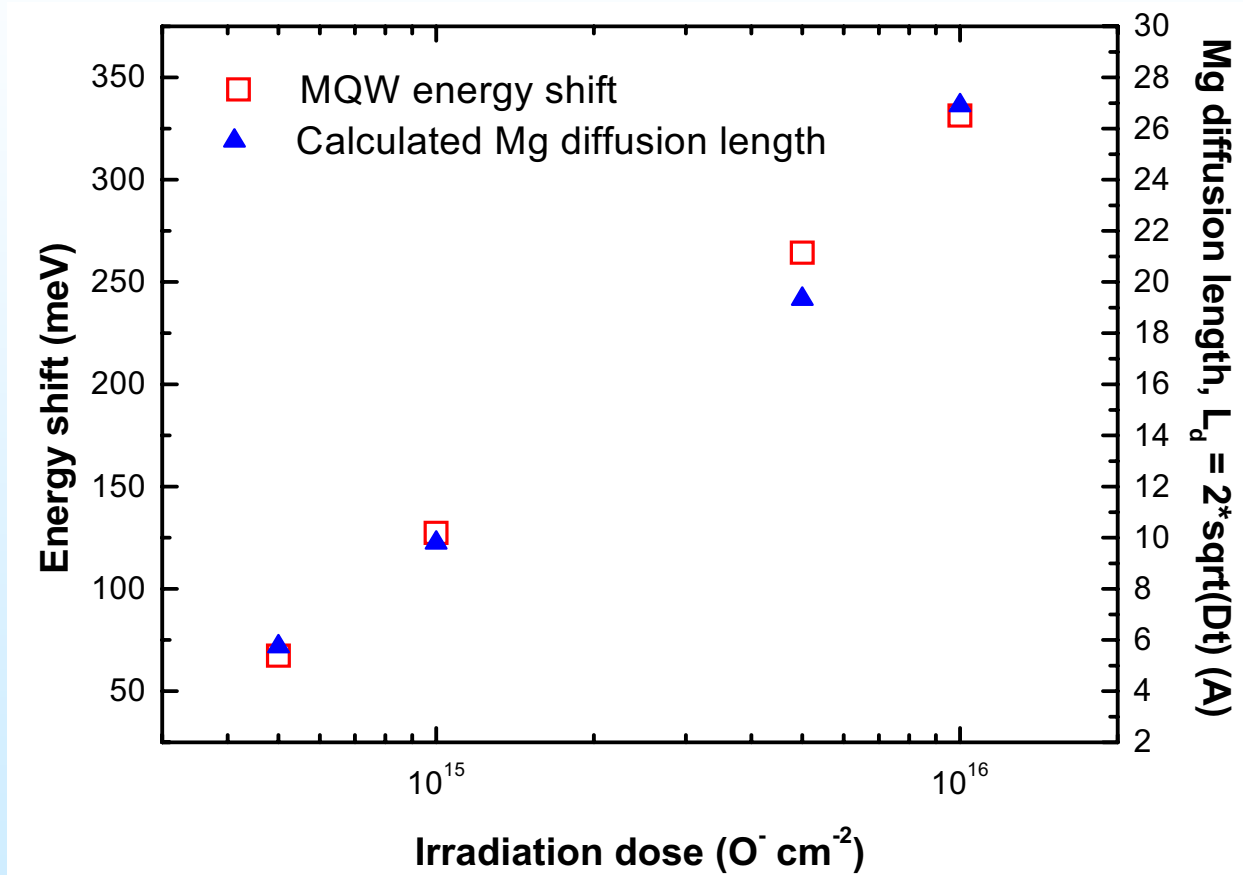
- Implanted a-axis epitaxial MQW ZnO(2 nm)/Zn_{0.7}Mg_{0.3}O(5.5 nm) sample with low energy oxygen ions. Low doses in the range 5×10^{14} O-cm⁻² – 1×10^{16} O-cm⁻²
- Following implantation, MQW samples were annealed for 60 s at 800 °C under Ar ambient. Energy shifts, caused by interdiffusion of Mg and Zn species between the well and barrier were observed with CL spectroscopy
- Study on unimplanted MQW samples showed them to be thermally stable under this annealing regime, meaning that all observed changes arose as a result of defects introduced during implantation



CL spectra of O implanted ZnO/ZnMgO MQW sample implanted with varying doses of O ions and RTA at 800 °C for 60s under Ar Ambient



Diffusion length, L_d and peak energy shift as a function of implantation dose

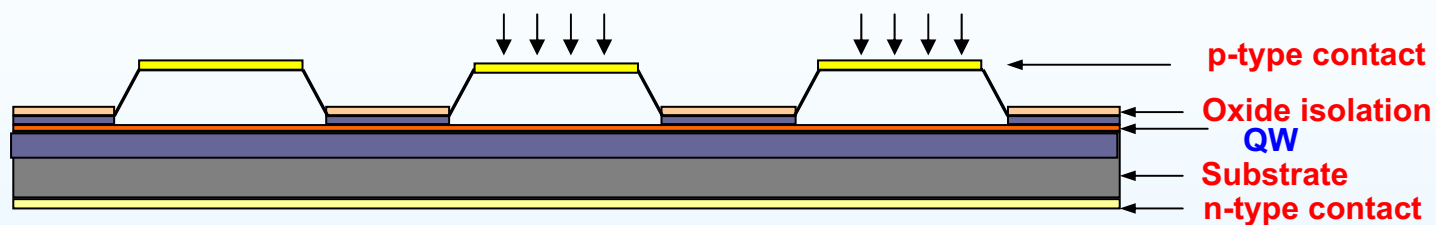


V. Coleman et al, Semicond. Sci. Technol. 21, L25 (2006)

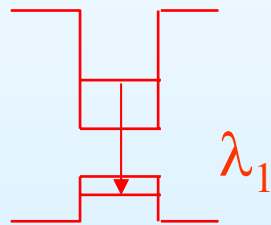
Tuning the Emission Wavelength of GRINSCH Quantum Well Lasers

GaAs/AlGaAs QW Lasers

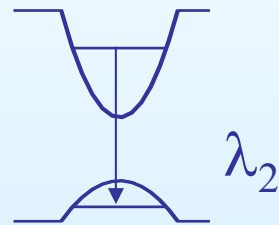
Multi Wavelength Lasers



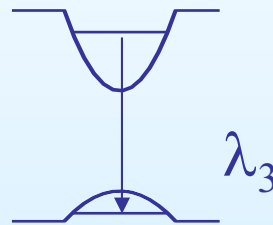
un-implanted



dose A

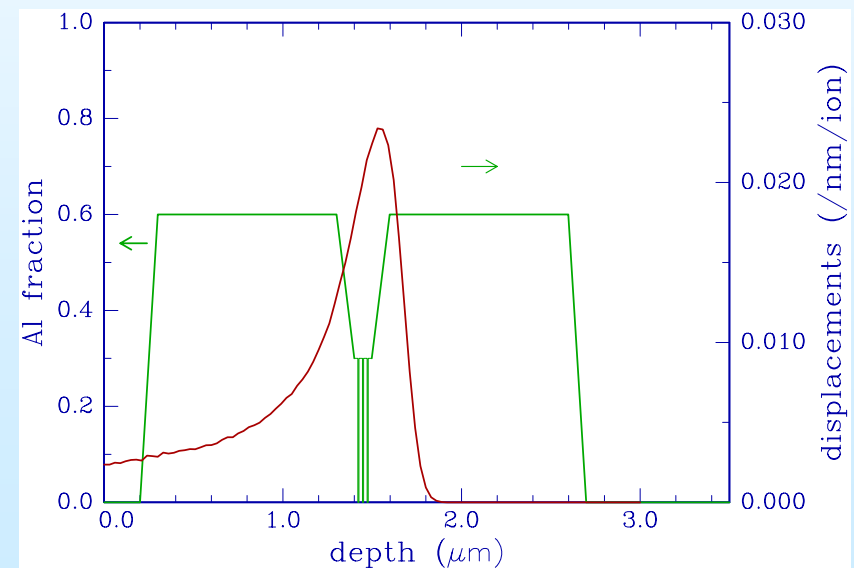


dose B



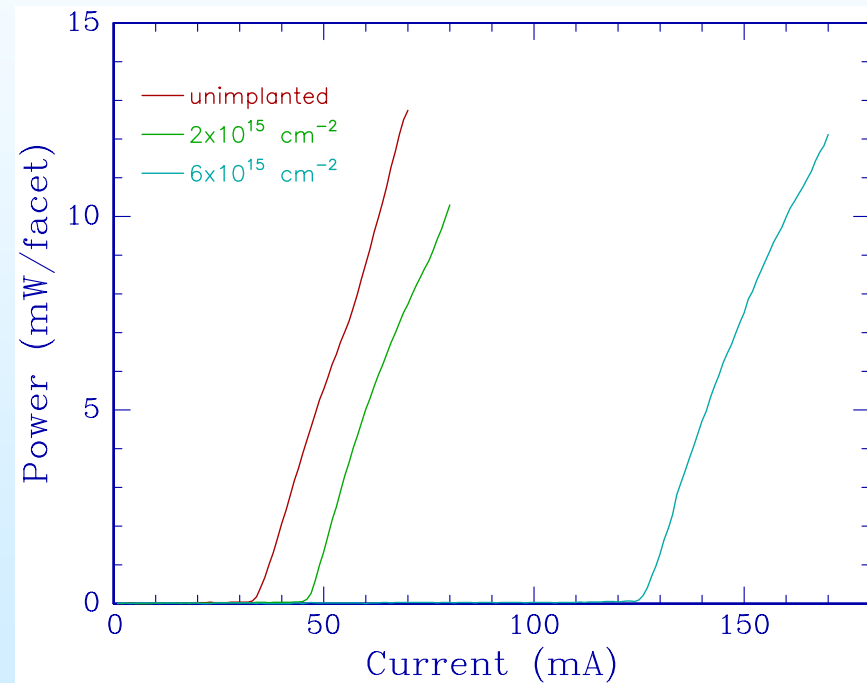
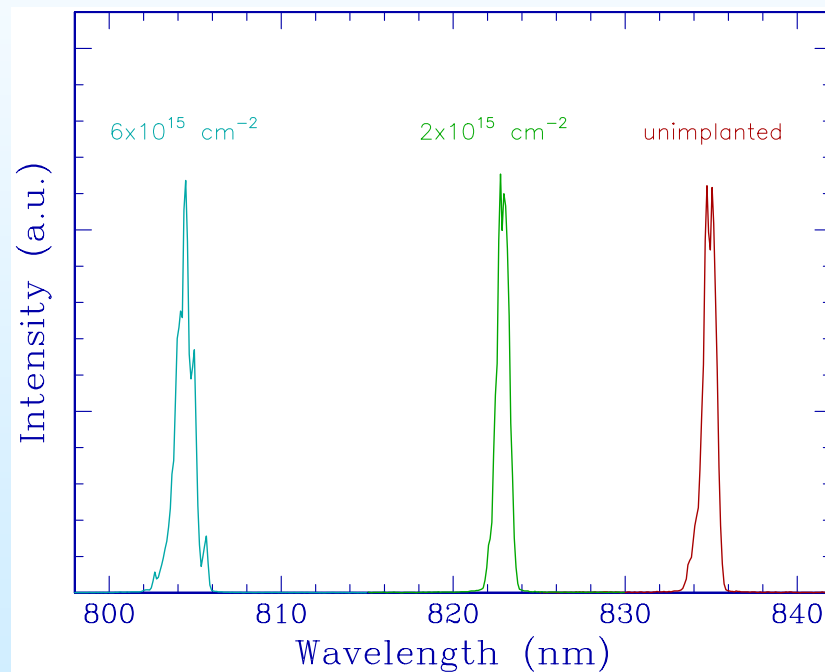
dose A < dose B

$\lambda_1 > \lambda_2 > \lambda_3$



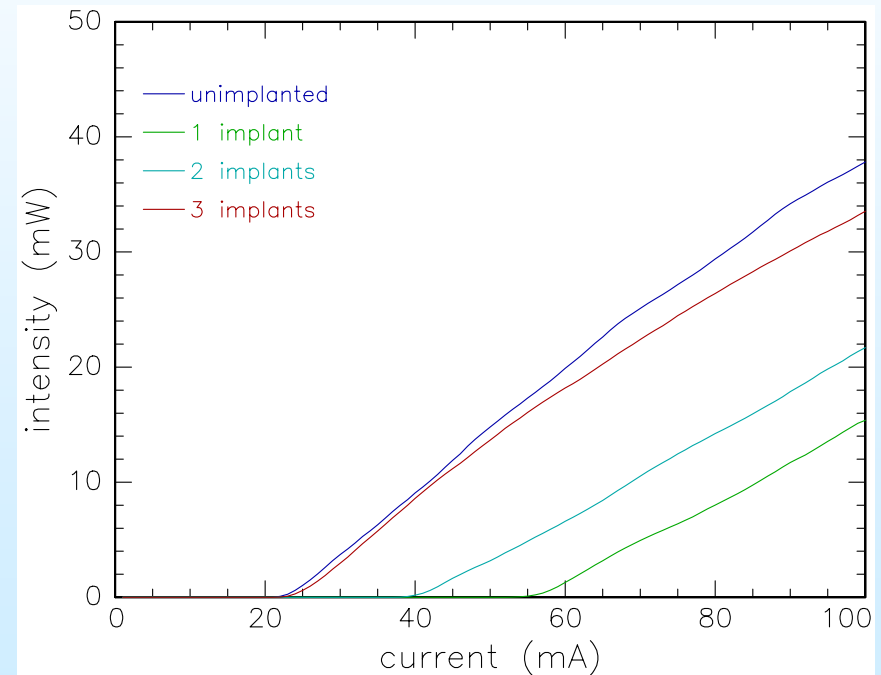
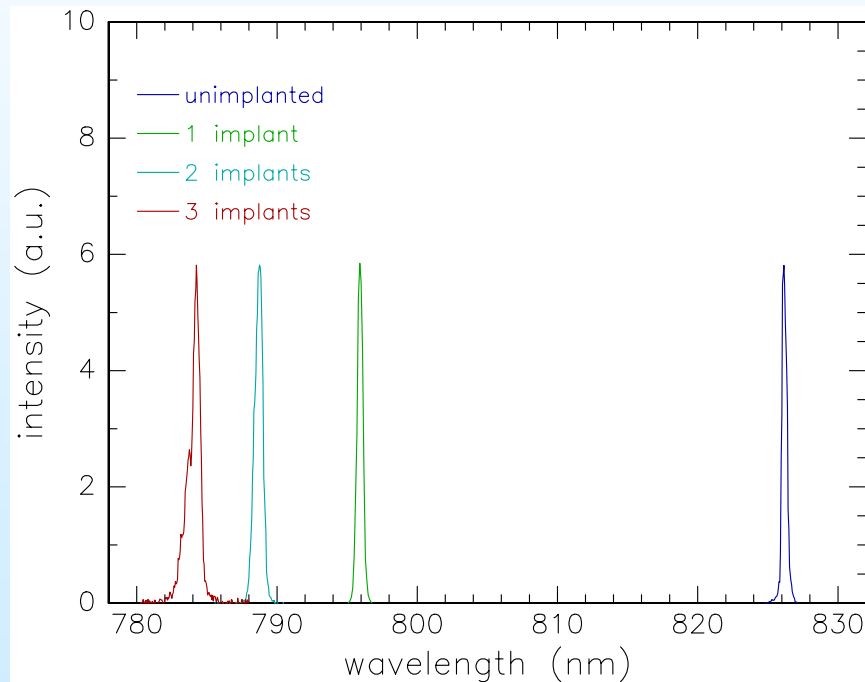
Lasing Spectra and L-I Characteristics of GaAs/AlGaAs QW Lasers

(900°C, 60 sec)



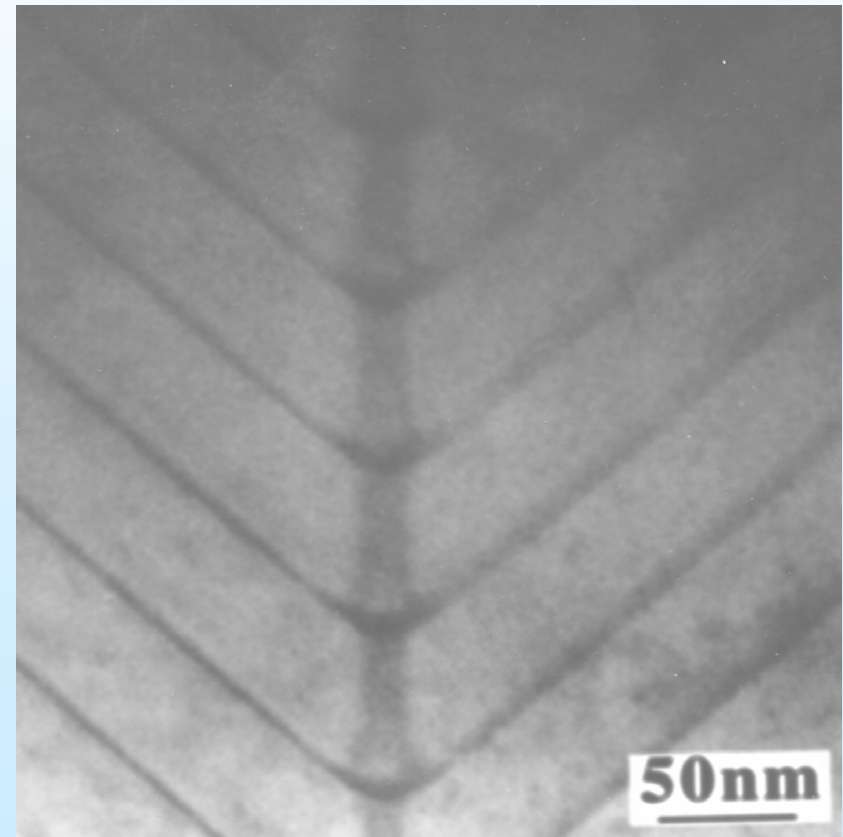
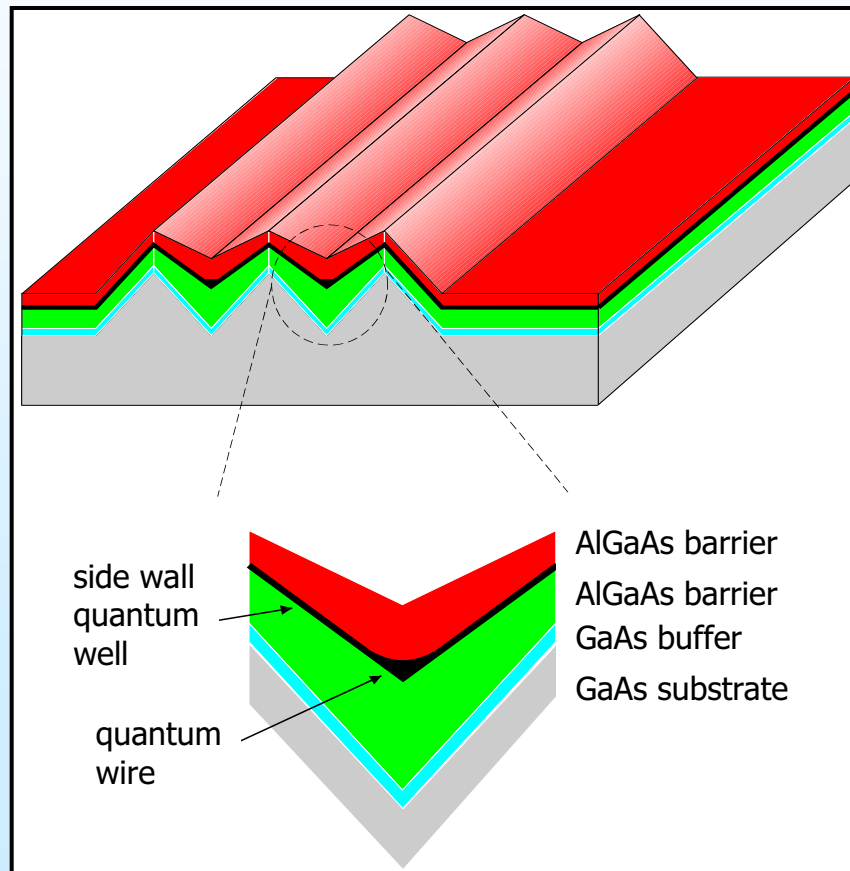
H.H. Tan and C. Jagadish, Appl. Phys. Lett. 71, 2680 (1997).

Multi-Step Implantation Scheme for Improved GaAs/AlGaAs QW Laser Performance

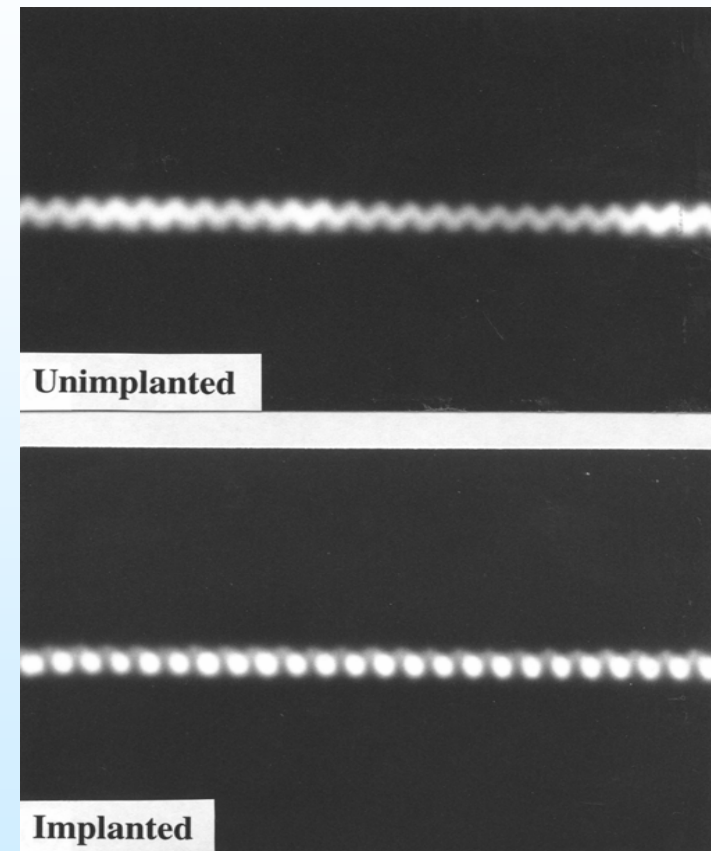
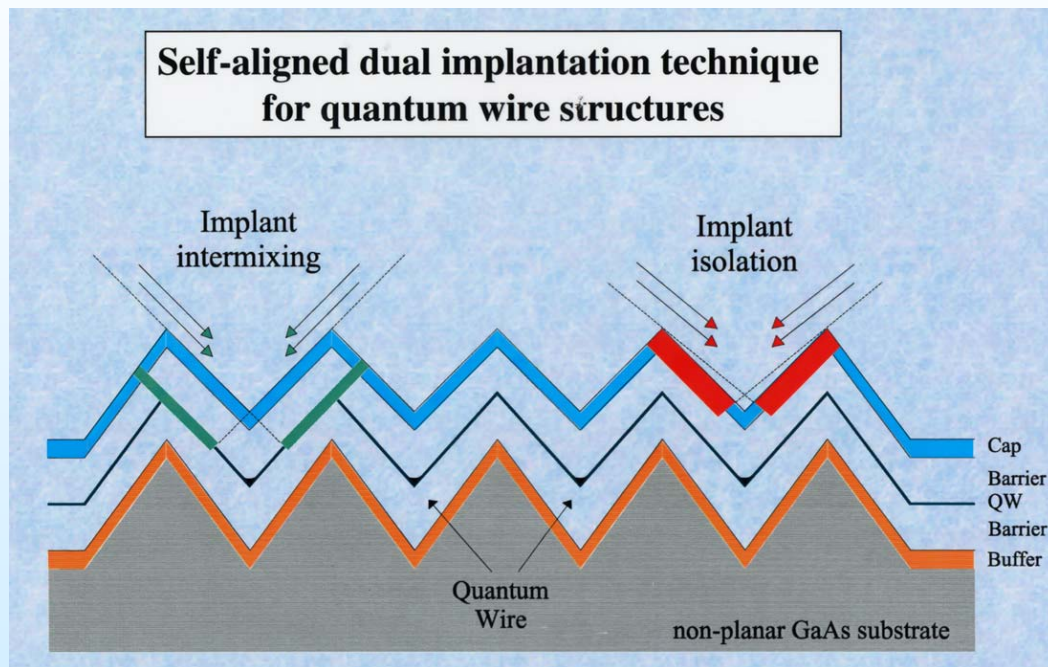


Quantum Wire Lasers

Cross-sectional TEM of GaAs-AlGaAs quantum wire structure

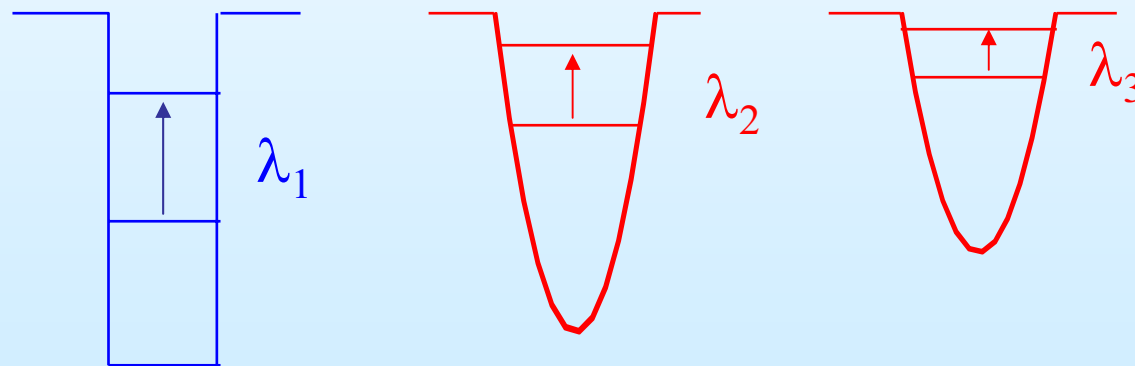
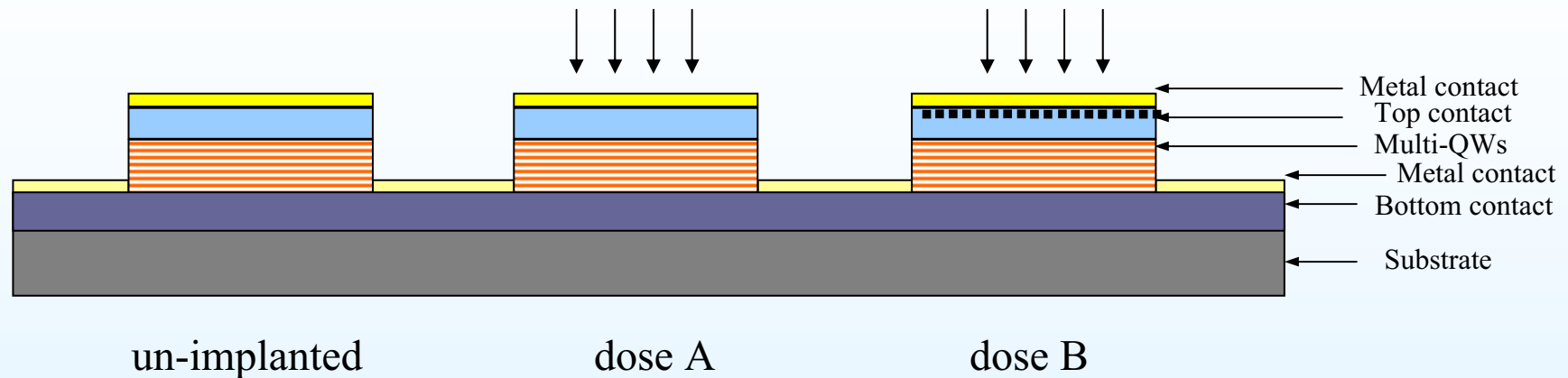


Light emission from quantum wire laser array



Tuning the Detection Wavelength of Quantum Well Infrared Photodetectors (QWIPs)

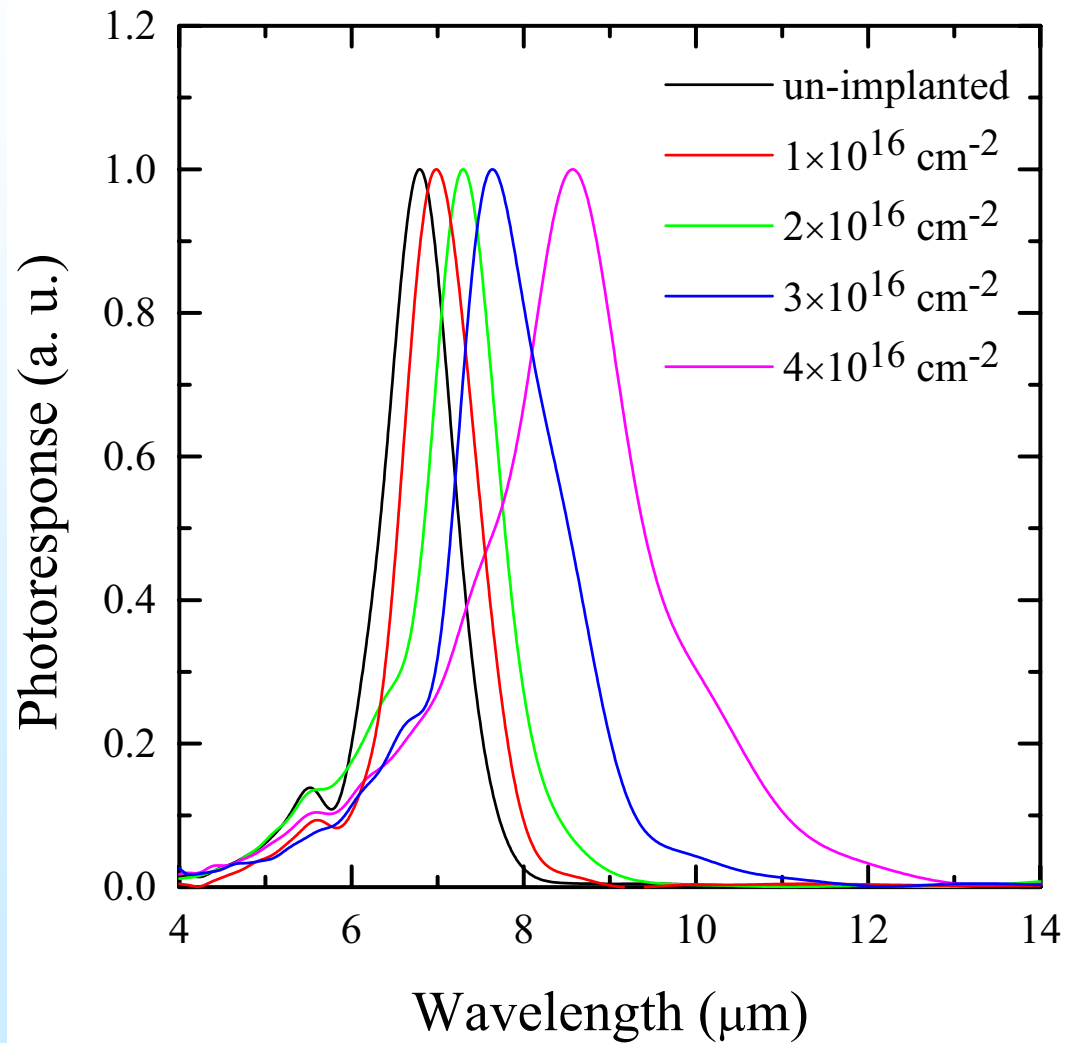
Tuning the wavelength of QWIP



dose A < dose B

$$\lambda_1 < \lambda_2 < \lambda_3$$

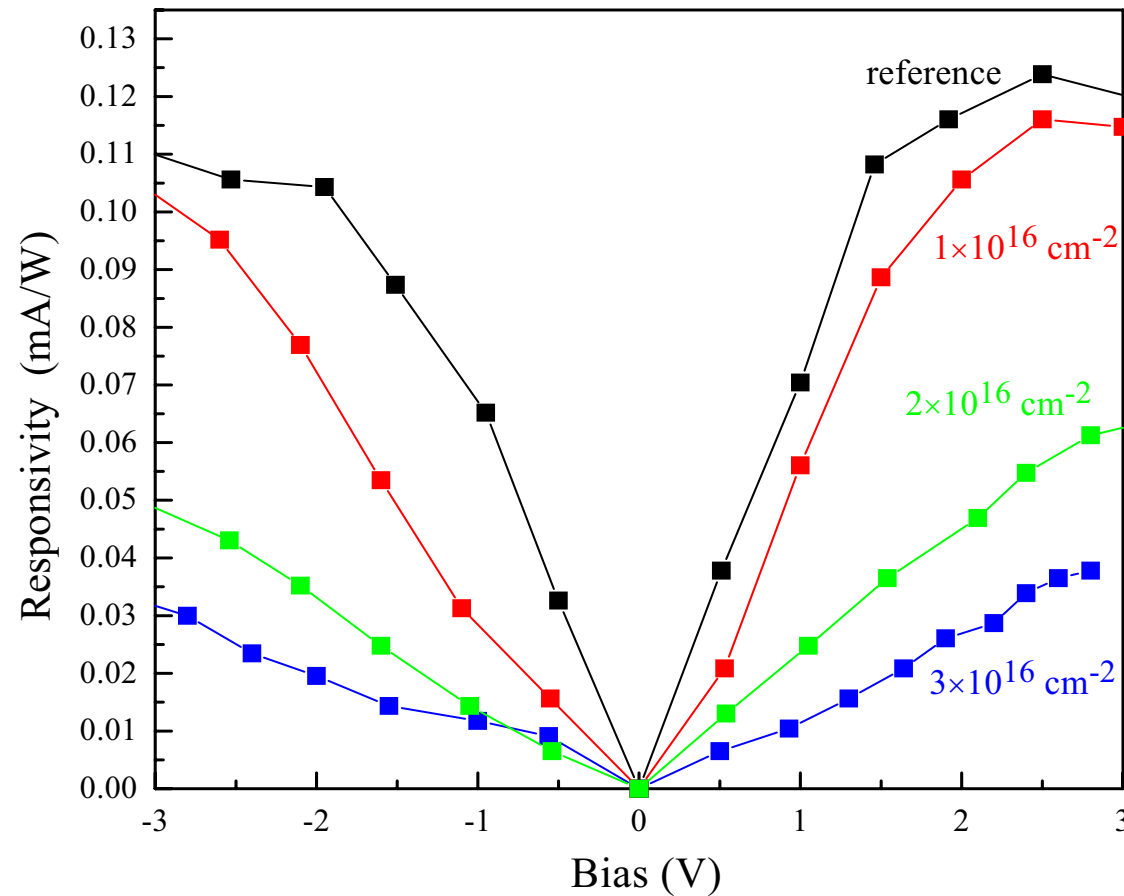
QWIP spectral response



950°C, 30 sec

L. Fu et al,
Appl. Phys. Lett.
78, 10 (2001).

Responsivity



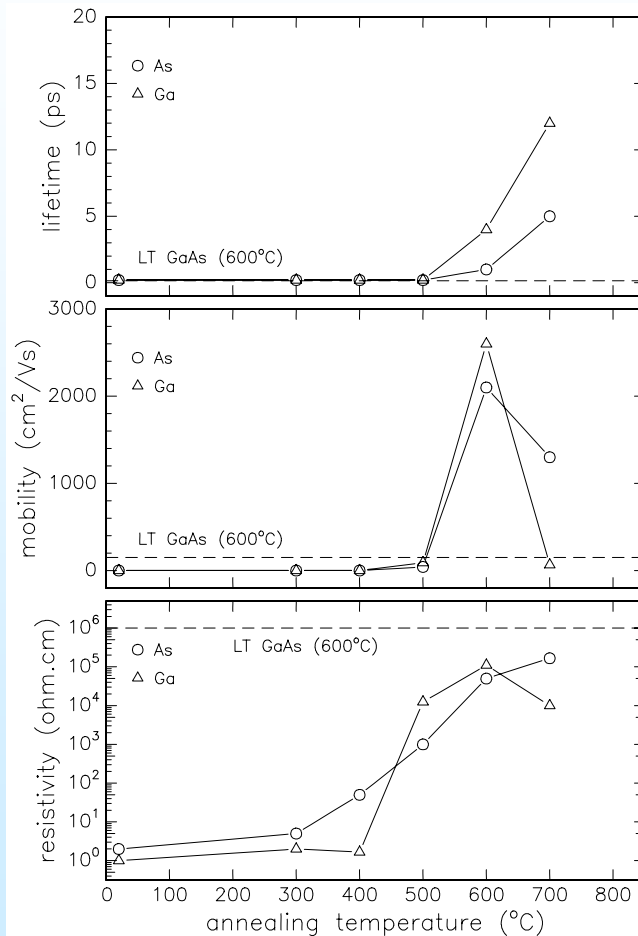
L. Fu et al, Appl. Phys. Lett. 78, 10 (2001).

Overview

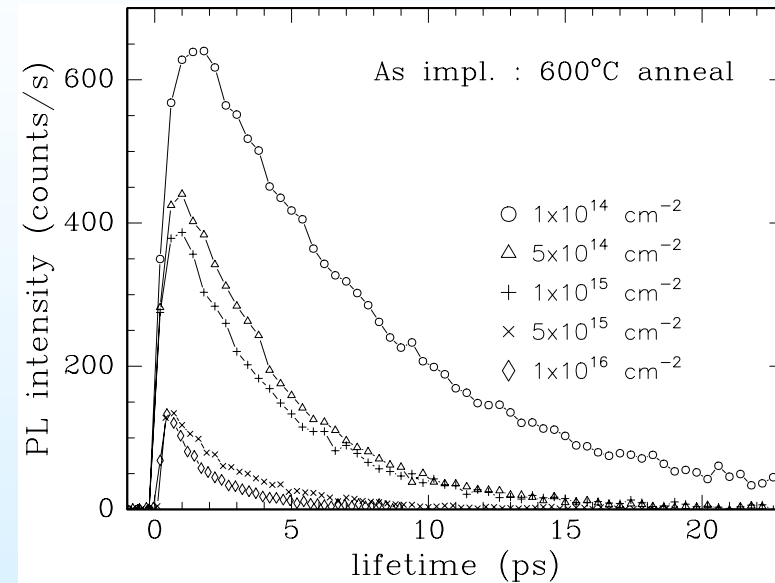
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Implantation for Ultrafast photodetector materials

Ultrafast photodetector materials - GaAs



2 MeV Ga/As into SI GaAs, dose = $1 \times 10^{16} \text{ cm}^{-2}$



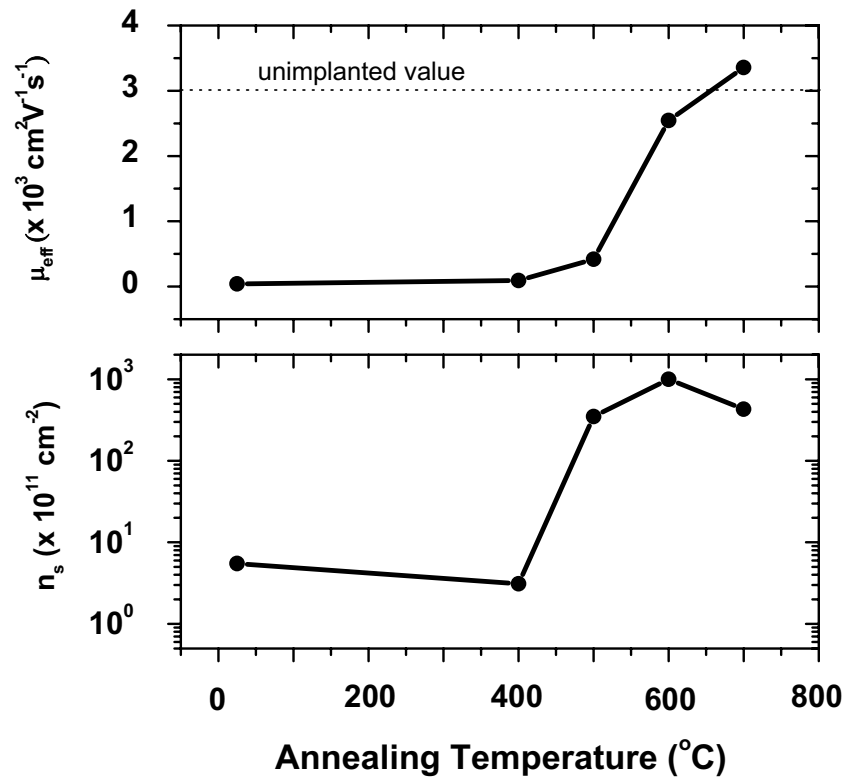
At low annealing temperature:

- very short carrier lifetimes,
- low mobility and low resistivity

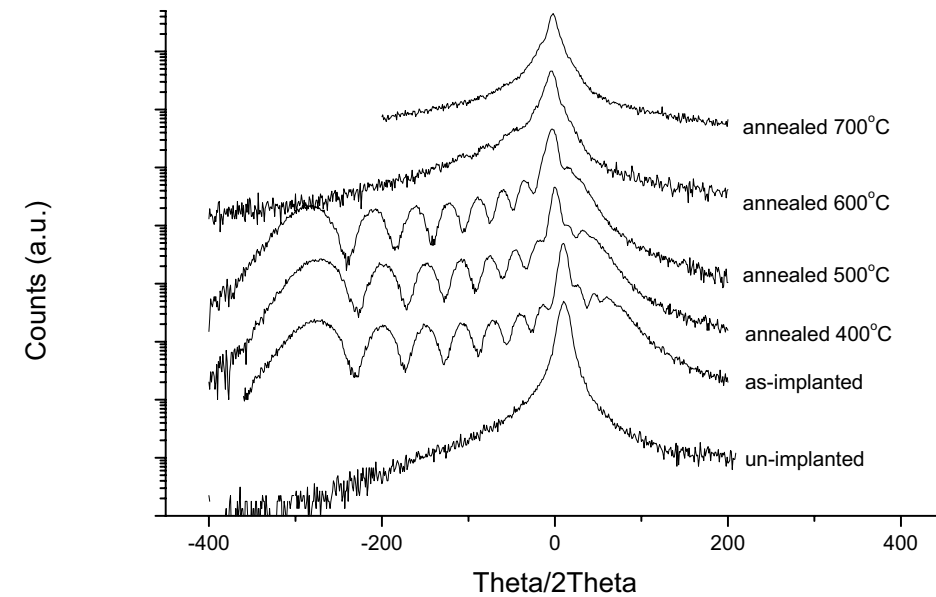
At 600°C annealing:

- short carrier lifetimes - ps range,
- high mobility and high resistivity

Ultrafast photodetector materials - InP



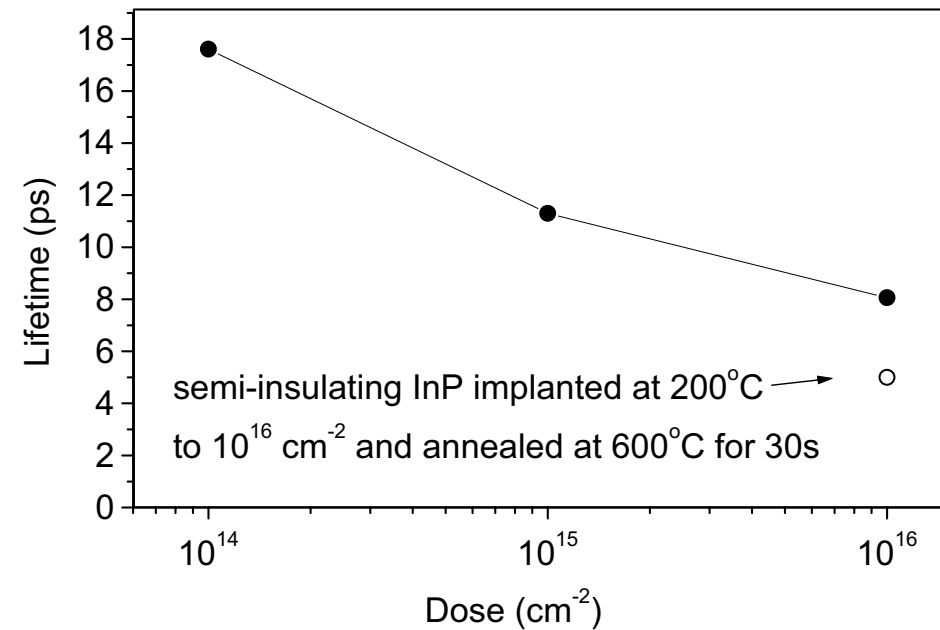
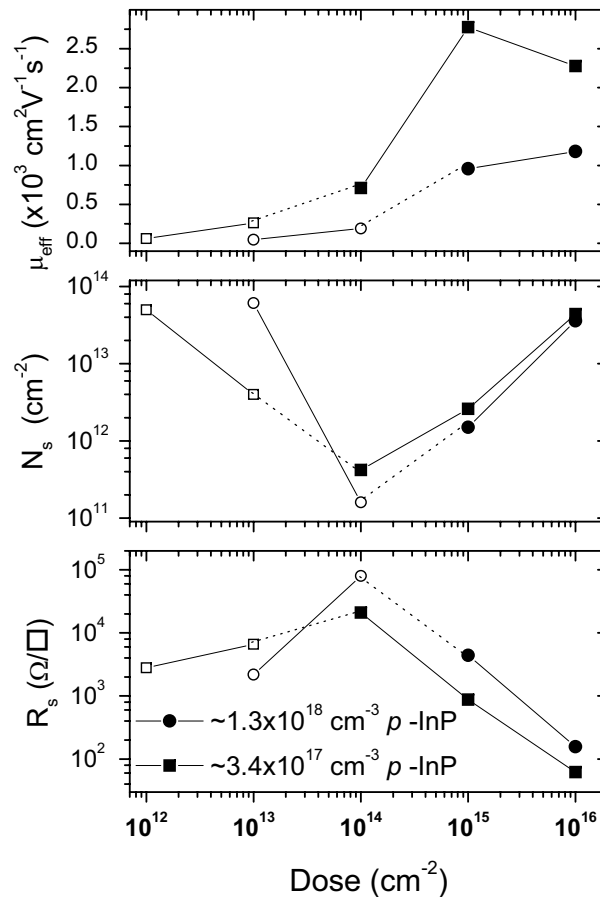
1 MeV P into SI InP, dose = $1 \times 10^{16} \text{ cm}^{-2}$



- At 600-700 $^{\circ}\text{C}$, recovered most crystalline damage and original mobility
- Increased carrier concentration with annealing temperature (due to shallow donors)

C. Carmody et al., J. Appl. Phys. 94, 1074 (2003)

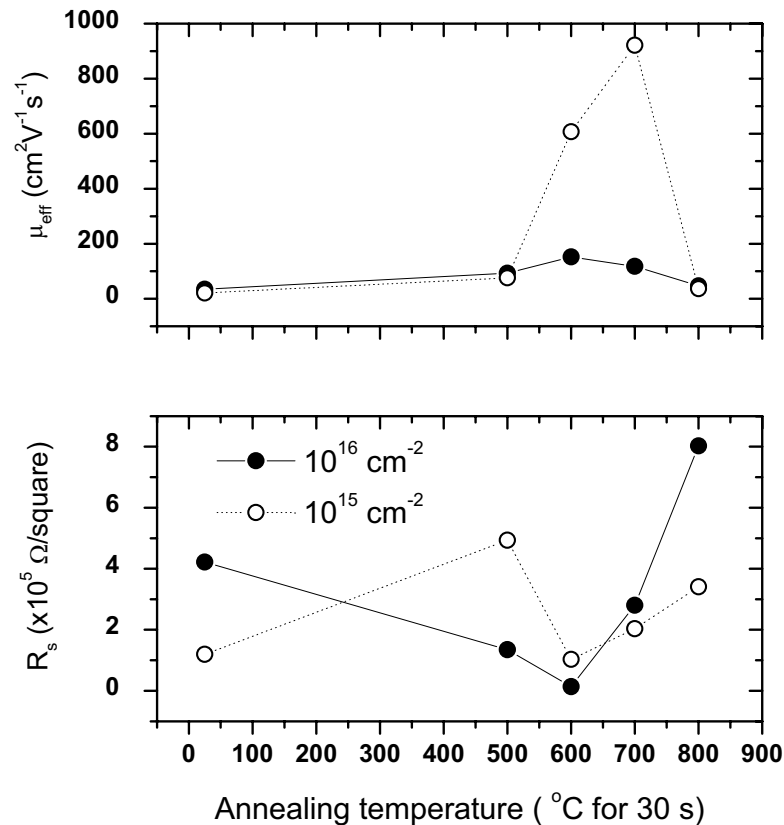
Ultrafast photodetector materials - InP



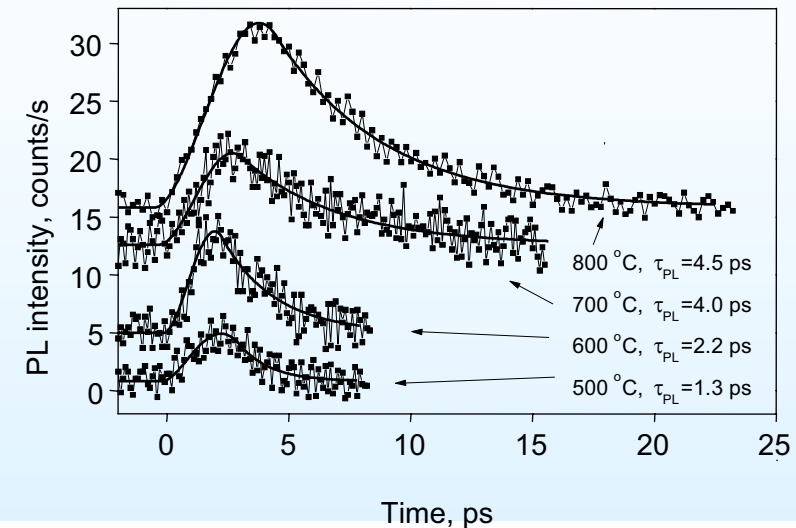
- By implanting into p-type, the shallow donors can compensate the acceptors
- Short lifetimes with high mobility and high resistivity could be achieved

1 MeV P into p-type InP, annealed 600°C , 30s C. Carmody et al., J. Appl. Phys. 94, 1074 (2003)

Ultrafast photodetector materials - InGaAs



2 MeV Fe into InGaAs



- **Implantation creates shallow donors, as in InP**
- **Higher dose required to achieve high resistivity, hence no luminescence observed due to highly defected material**
- **Use Fe instead as it creates a deep level**
- **ps lifetimes and with reasonable resistivity, mobility maybe achieved**

C. Carmody et al., Appl. Phys. Lett. 94, 1074 (2003)

Summary of ultrafast photodetector materials by implantation

GaAs

- **Relatively easy - ps lifetimes, high resistivity, high mobility**
- **Compromise btw carrier lifetimes and resistivity/mobility**

InP

- **Implantation creates shallow donor**
- **Hence, need p-type material and careful control of impl. dose**
- **ps lifetimes, high resistivity, high mobility achievable**

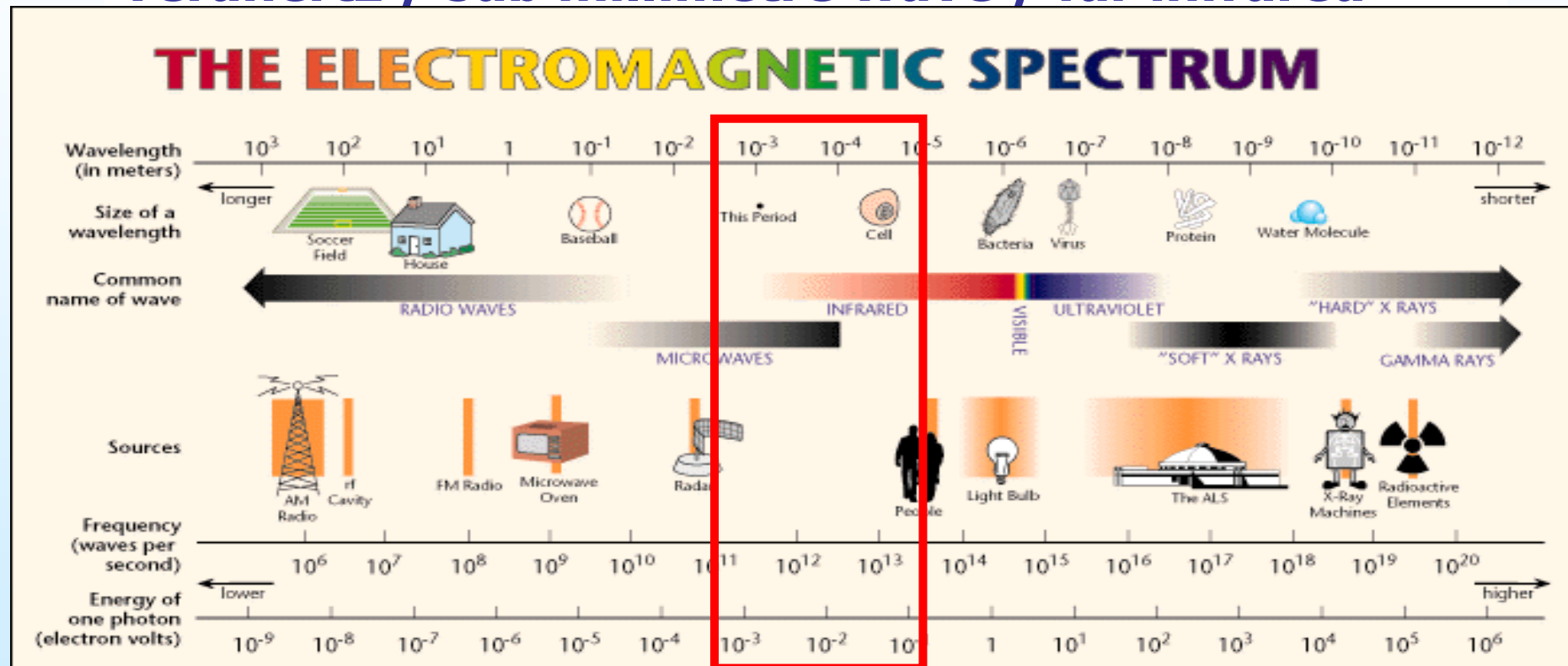
•InGaAs

- **Implantation creates shallow donor**
- **Higher implantation dose required, compared to InP (highly defective material)**
- **By using Fe (deep trap), ps lifetimes with reasonable resistivity, high mobility achievable**

Implanted III-V Materials for THz Emitters

How do we define "THz Radiation"?

Terahertz / sub millimetre wave / far infrared



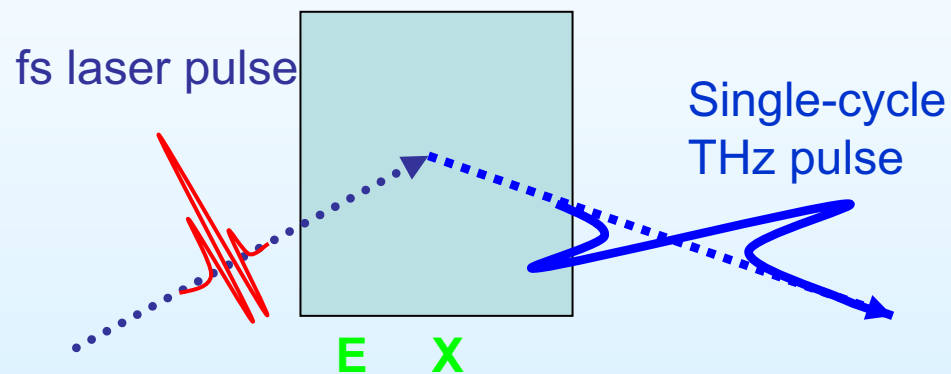
UNITS: 1THz / 1ps / 300 μ m / 4.1meV / 47.6K

Why are we interested in THz photonics?

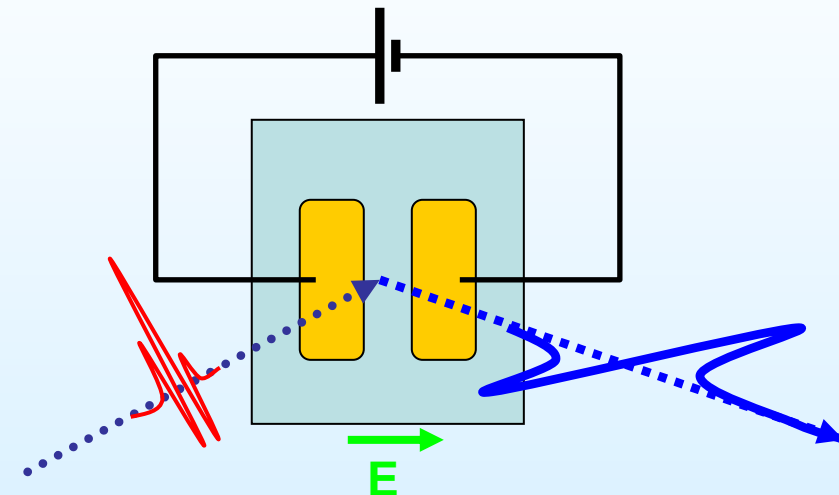
- THz spectroscopy covers energy range of correlated systems (excitons, Cooper Pairs, phonons, plasmons...)
- Also energy range for molecular rotations and vibrations (plastic explosive detection)
- Non-contact probe of conductivity
- High resolution electric field detection in devices (chip diagnostics)
- Time resolved probe of dielectric properties of materials & devices
- Non ionising (medical/dental imaging)
- Non destructive testing (imaging faults)
- MANY MORE USES ACROSS DIVERSE FIELDS!!

Single-cycle terahertz emitters

Bulk semiconductor emitter



Photoconductive switch emitter



What optimization is required?

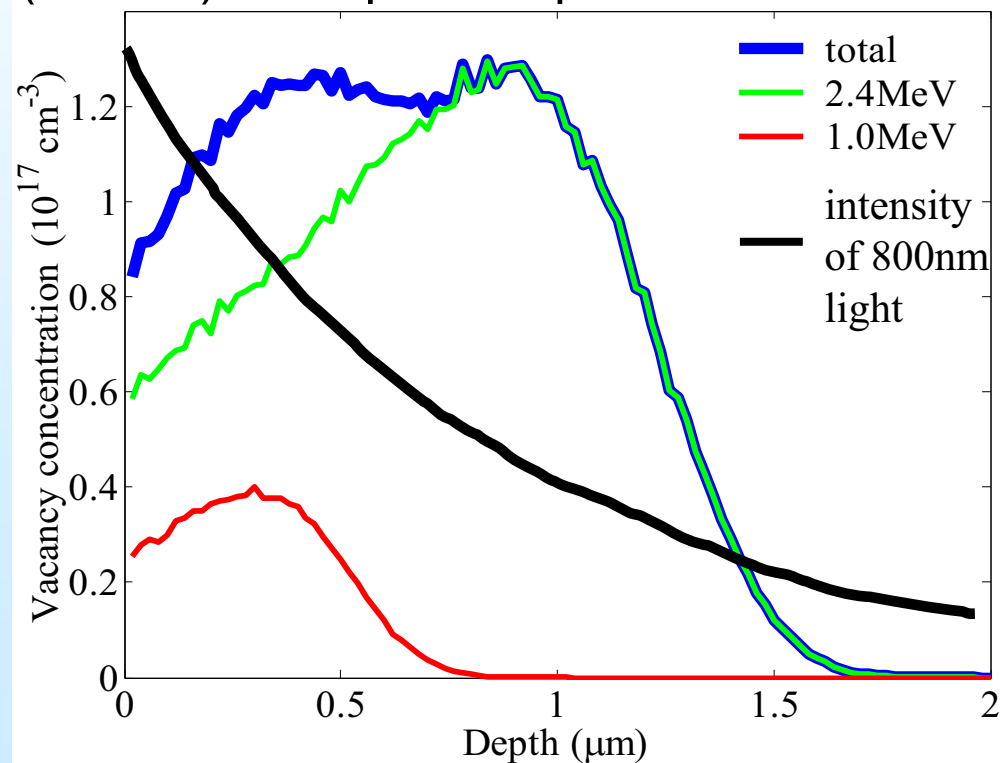
Improve spectral intensity

Increase bandwidth

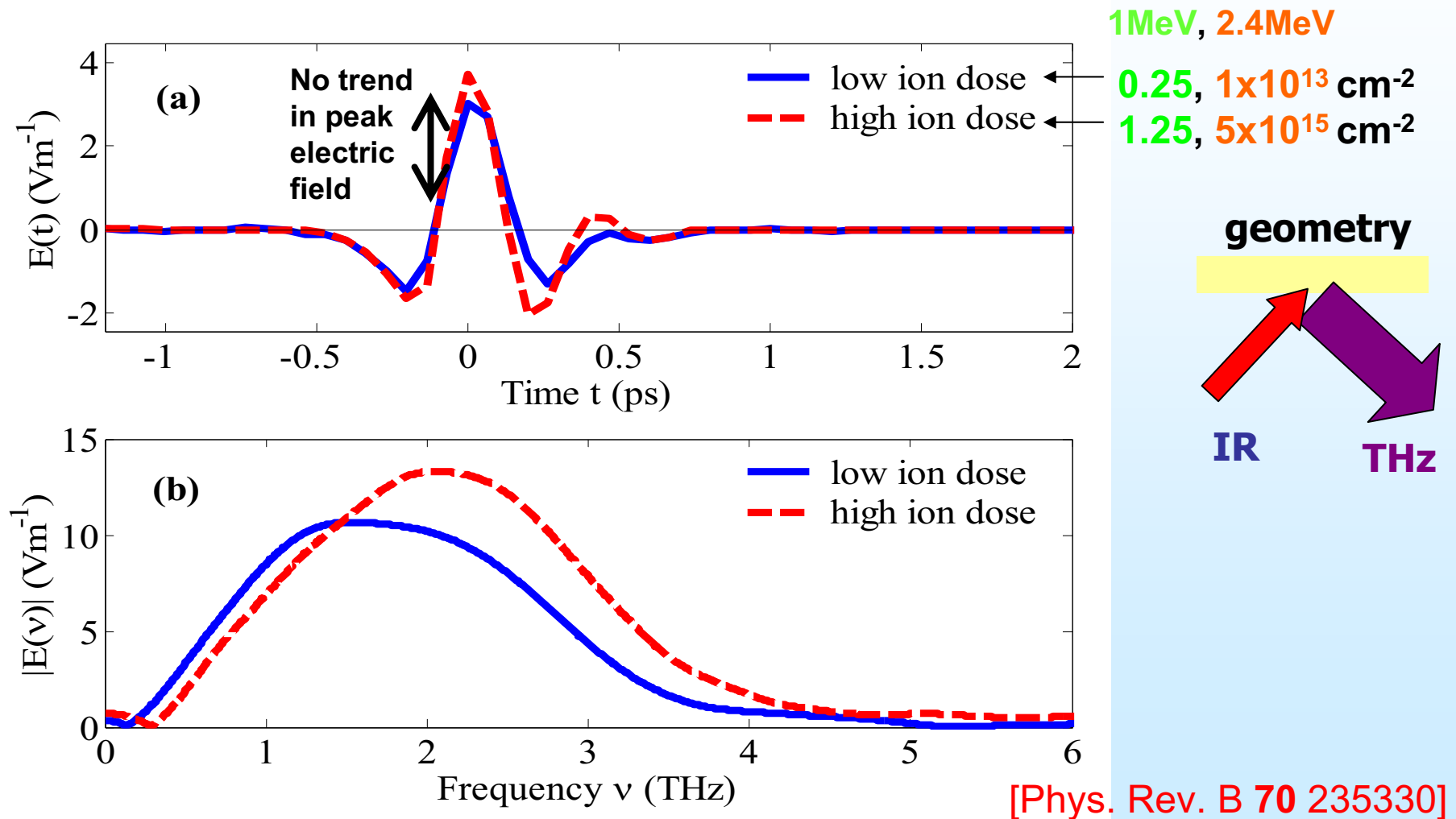
Ion implanted GaAs

[Phys. Rev. B **70** 235330; Appl. Phys. Lett. 86:254102 (2005)]

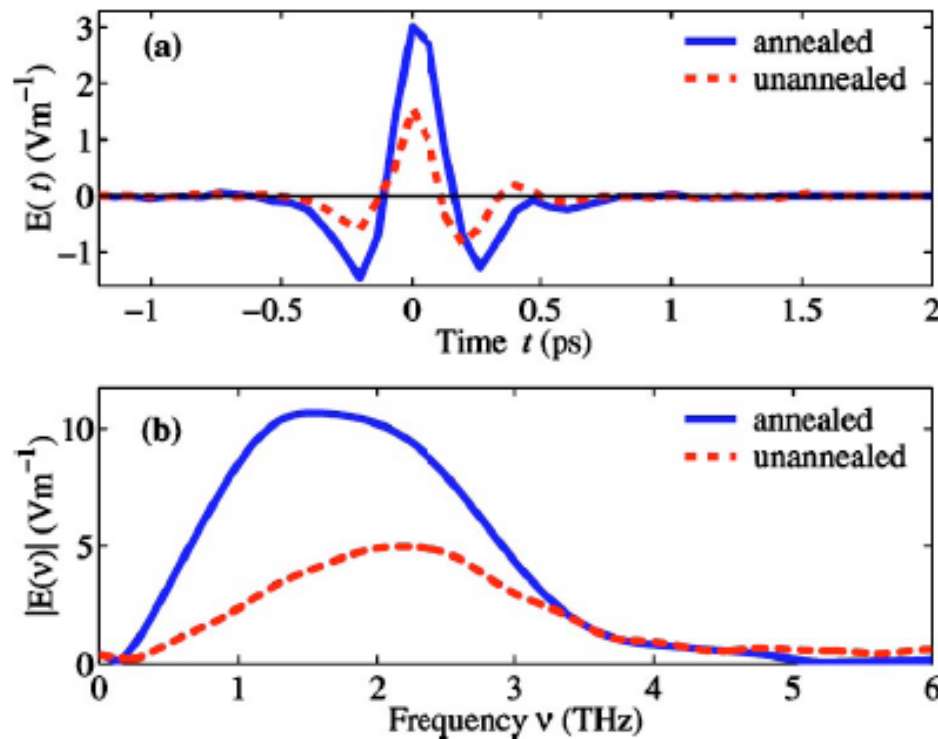
- GaAs was implanted with dual, high energy doses of As⁺ at 1MeV and 2.4MeV, creating:
 - An approximately uniform vacancy damage profile
 - Extending over the infrared (800nm) absorption depth of GaAs
- Past work used low energy (~200keV) As ions
[Appl. Phys. B: Lasers Opt. **72**, 151; J. Appl. Phys. **93**, 2996]
- Annealed at 500°C for 30 min to allow mobility to recover, while retaining ultrashort carrier lifetimes (~0.1ps)
[Appl. Phys. Lett. **66** 3304; **76** 1306]
- Also In_{0.53}Ga_{0.47}As:Fe⁺ and InP:Fe⁺



Terahertz emission from GaAs:As⁺ surfaces



Effects of Annealing on THz Emission

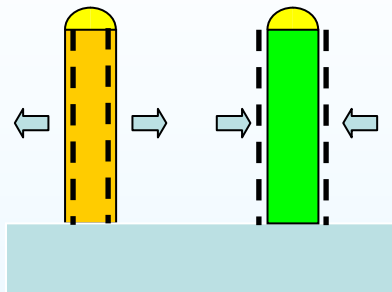


- ***For low implant dose, annealing causes an increase in maximum THz field from 1.6 V m⁻¹ to 3.0 V m⁻¹, but a decrease in the frequency of peak power from 2.1 THz to 1.6 THz.***

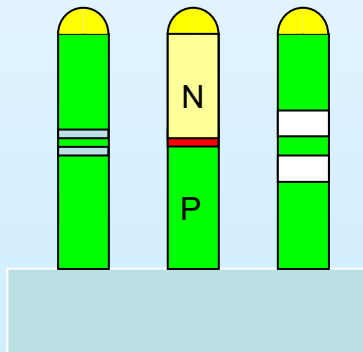
Overview

- Introduction
- Growth of Quantum Dots by Metal Organic Chemical Vapour Deposition (MOCVD)
 - InGaAs/GaAs, InAs/GaAs
 - InAs/InP, InAs/InGaAsP/InP
- Towards Quantum Well/Dot Photonic Integrated Circuits
 - Intermixing (QW/QD) by ion implantation, IFVD
 - Quantum Well/Dot Lasers
 - Quantum Well/Dot Infrared Photodetectors (QDIPs)
- **Nanowires**
Single Photon Sources / Detectors
Photonic Crystals
- Summary

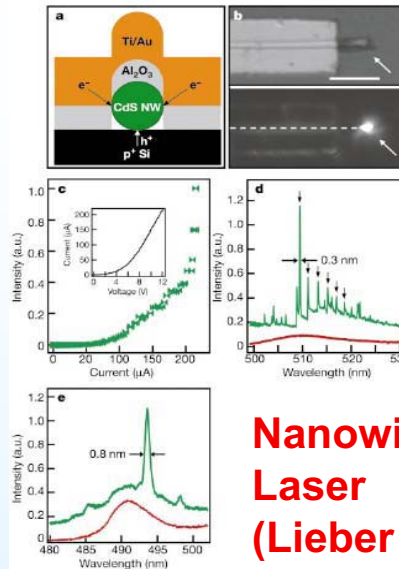
Nanowires



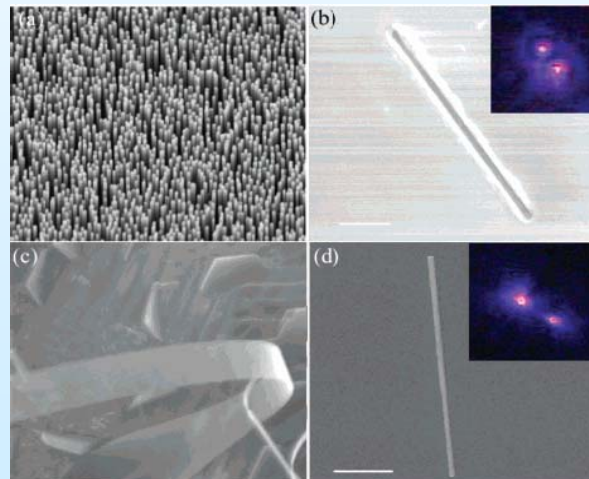
GaAs: 5.653 Å
InAs : 6.058 Å
Si : 5.431 Å



Exploration of truly one-dimensional
Heterostructure semiconductor devices

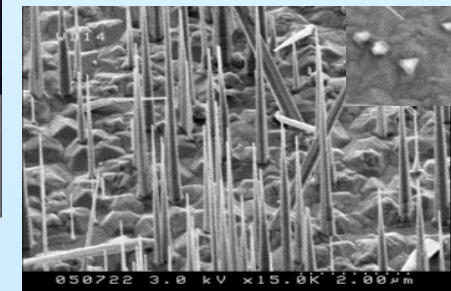


Nanowire
Laser
(Lieber group)



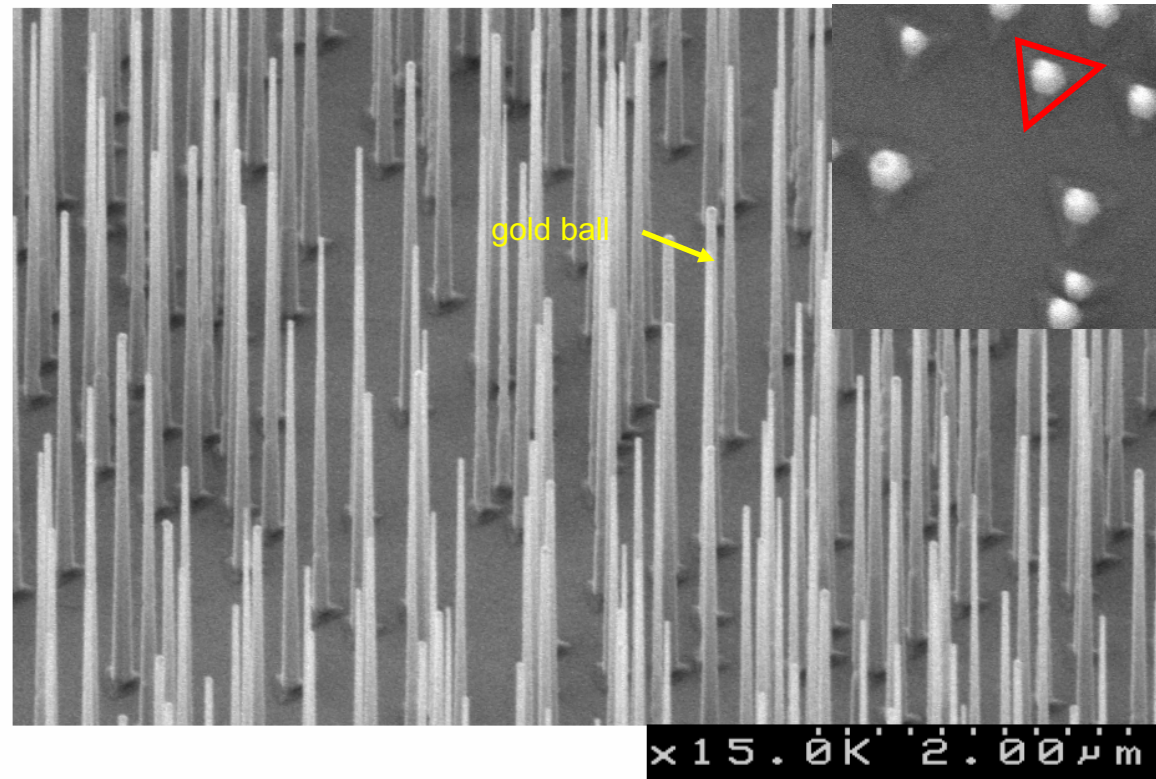
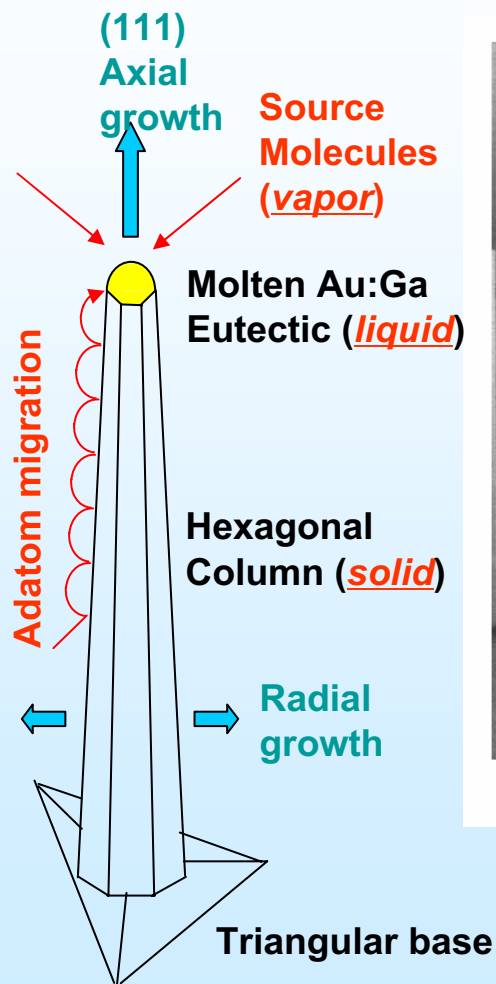
RTD (Samuelson group)

ZnO Nanowire laser
(Peidong Yang, UCB)



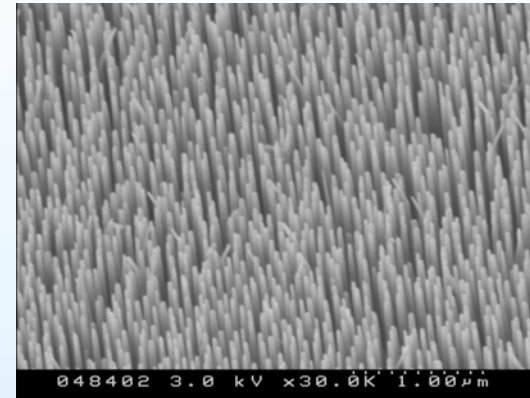
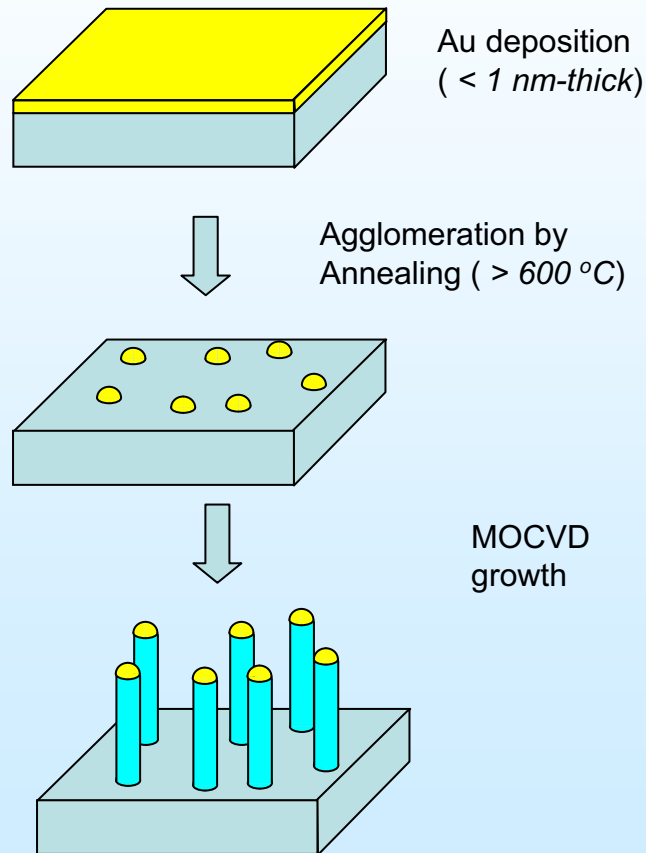
InAs on GaAs (ANU)

Vapor-Liquid-Solid Growth of GaAs (111)B nanowires



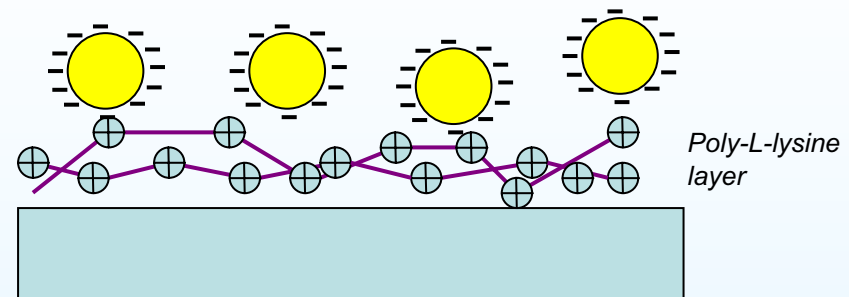
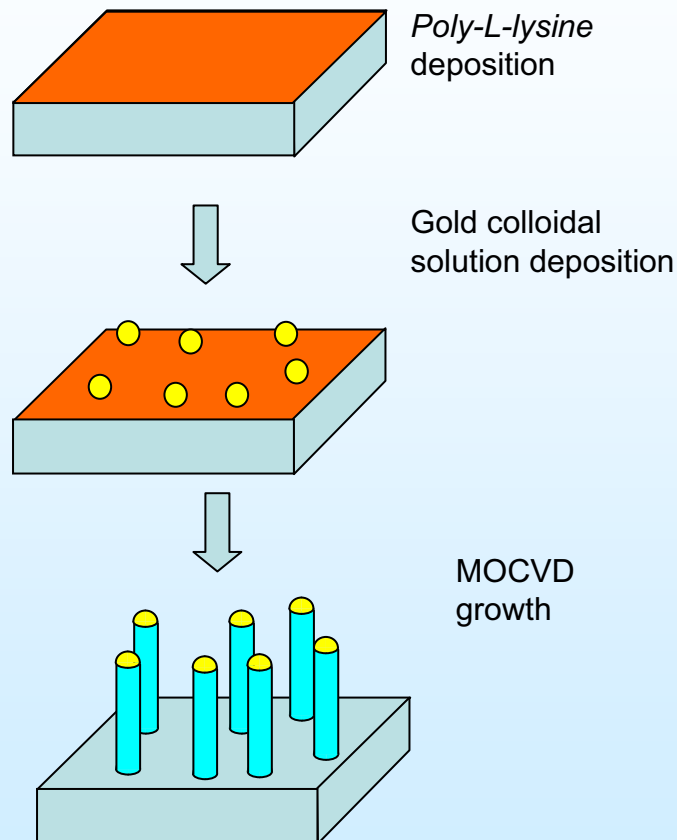
GaAs Nanowires grown using Gold Nanoparticles

Nanowires Growth Methods



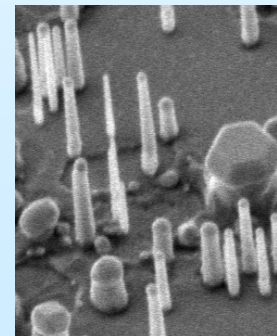
- Significant diameter dispersion of nanowires due to random agglomeration
- Poor reproducibility due to the difficulty in Au film thickness control
- Possible high optical/structural quality

Nanowires Growth Methods

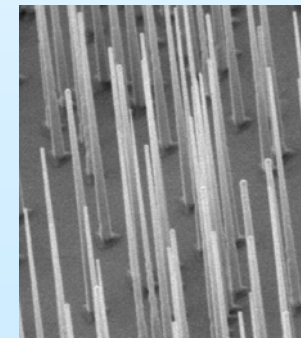


- Poly-L-lysine (*PLL*, one of polymer electrolytes)
- attracts negatively charged gold nanoparticles
 - prevents the agglomeration of gold nanoparticles

See the difference !

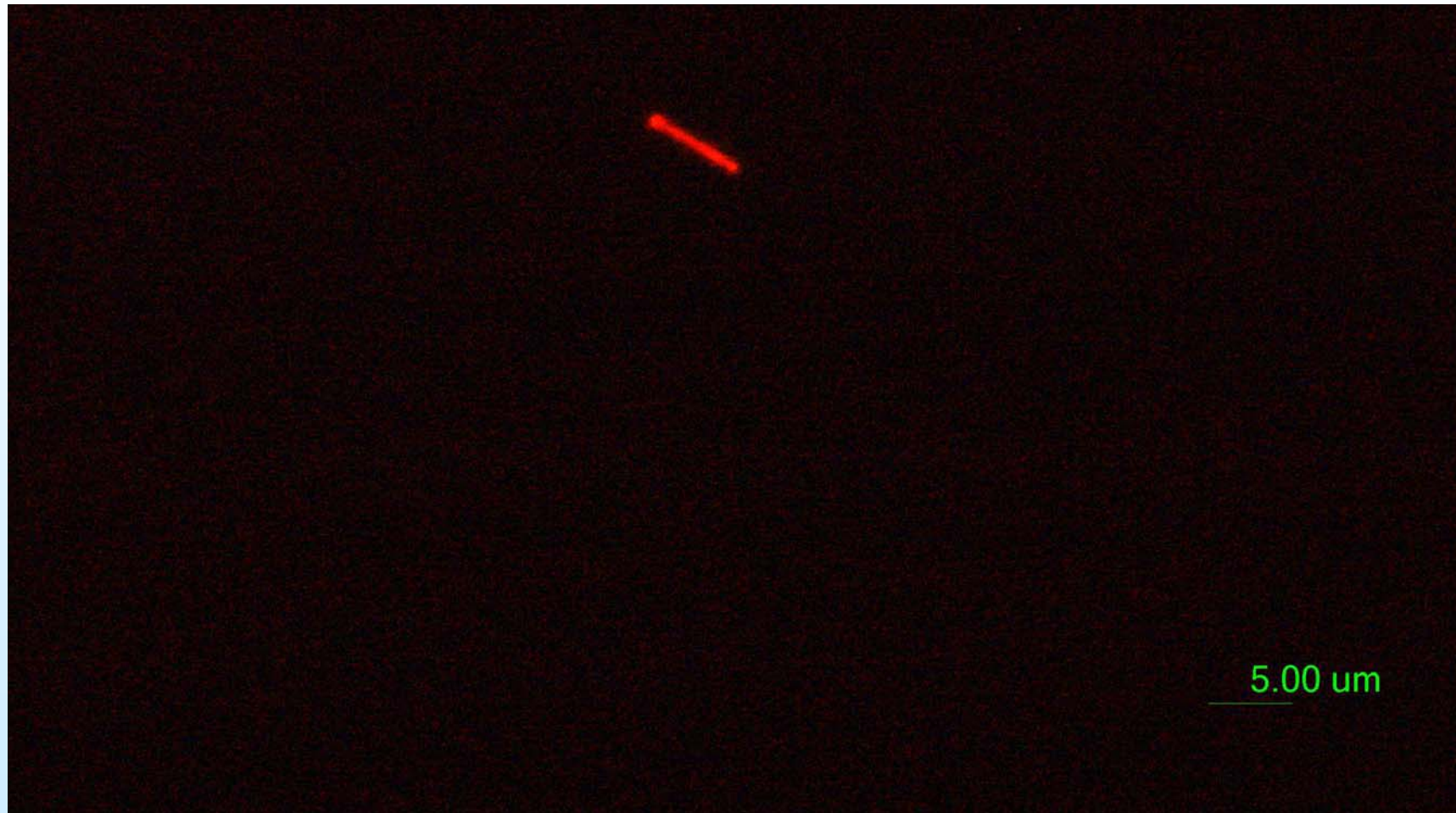


without *PLL* treatment

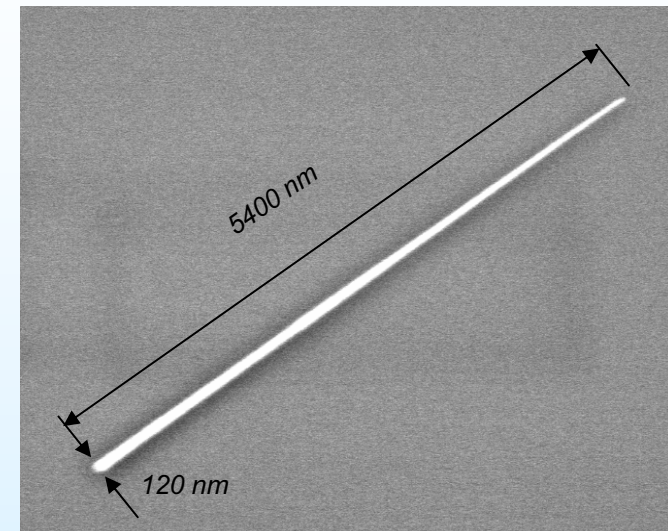
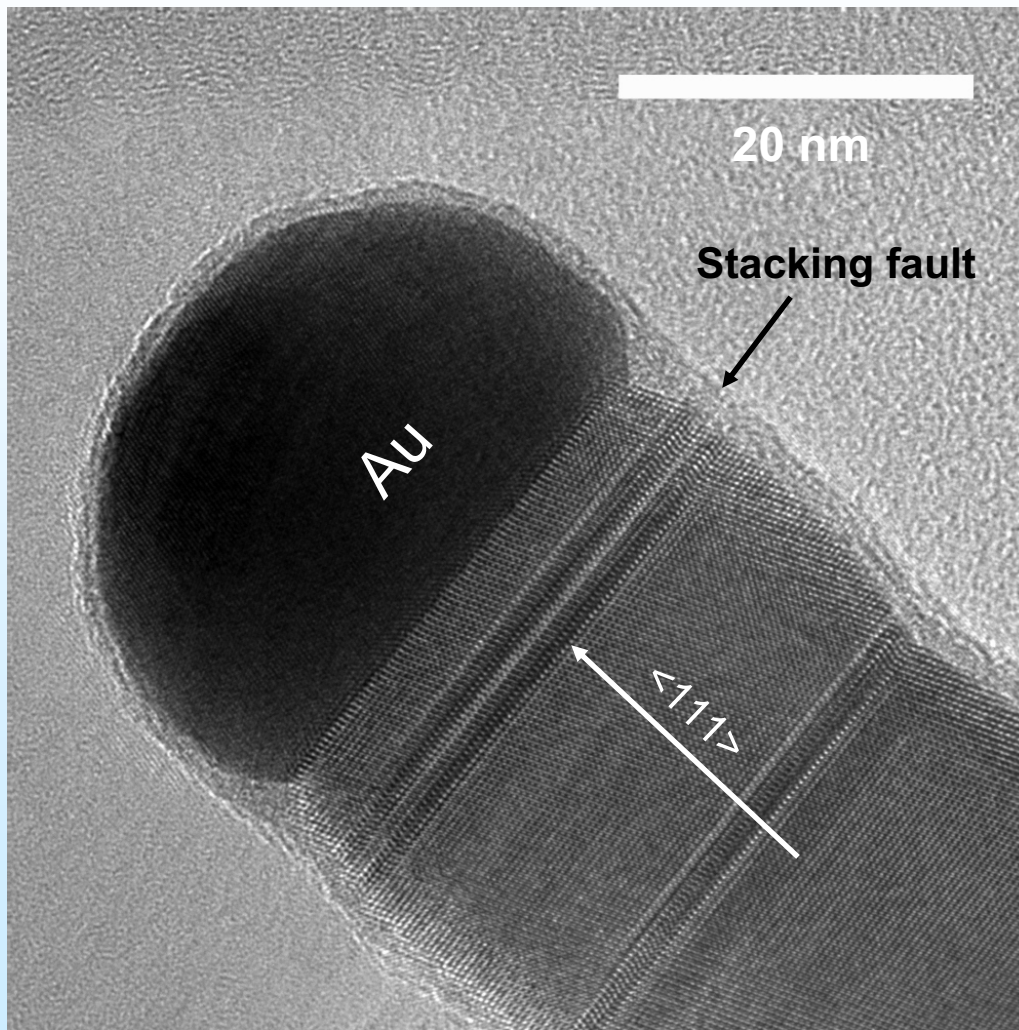


with *PLL* treatment

Image of a single GaAs NW PL



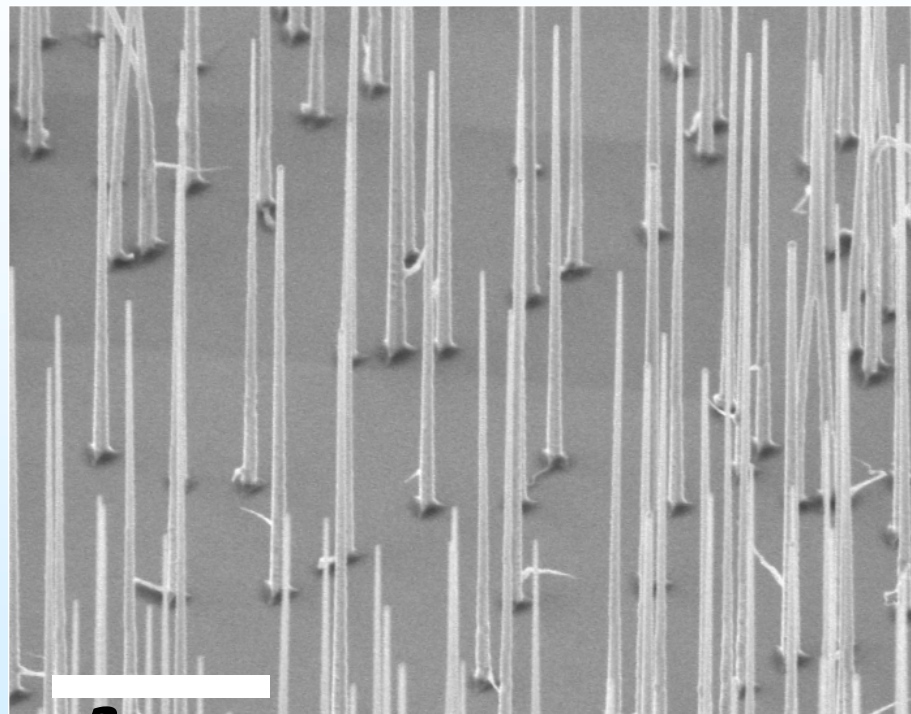
TEM of GaAs nanowire



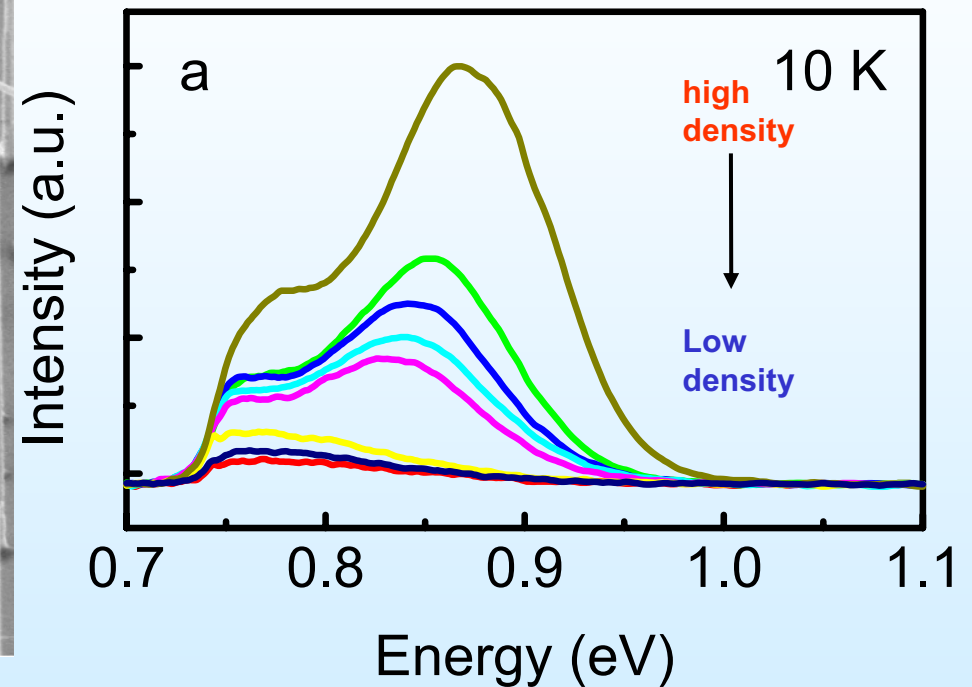
Sonicated GaAs nanowire grown @ 450 °C

- ❑ Perfect crystalline property except stacking faults

InGaAs nanowires on GaAs (111)

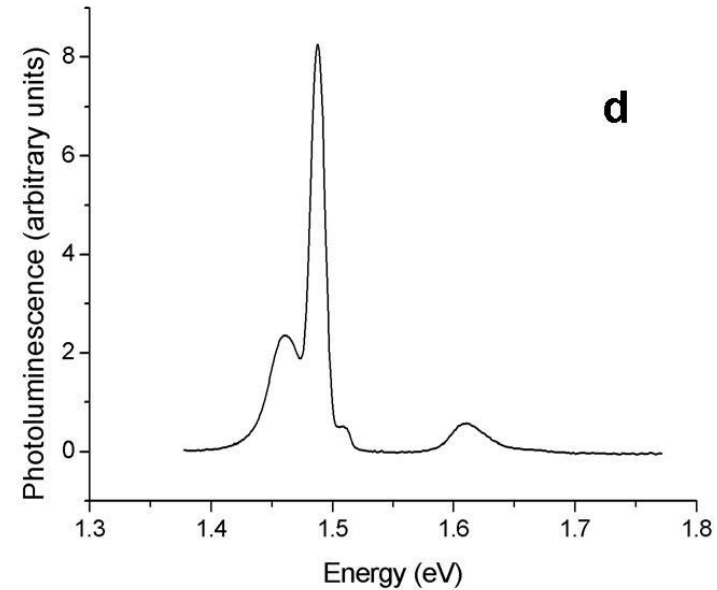
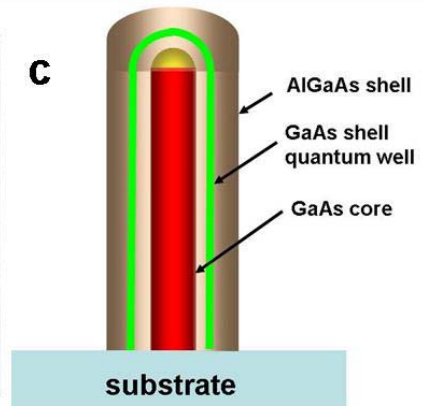
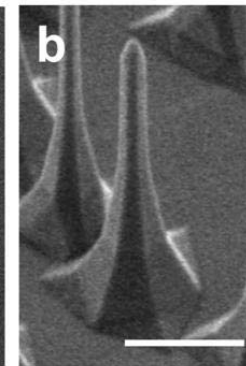
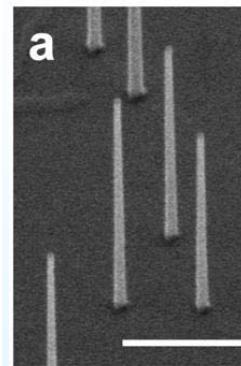
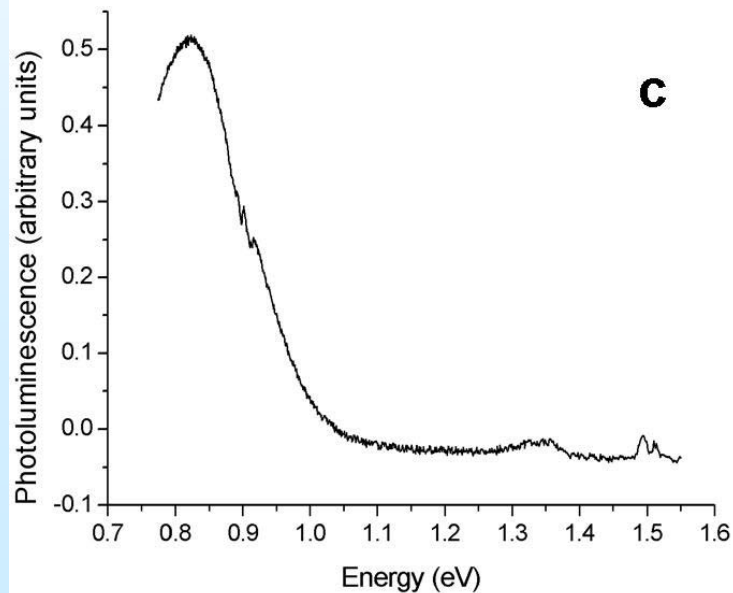
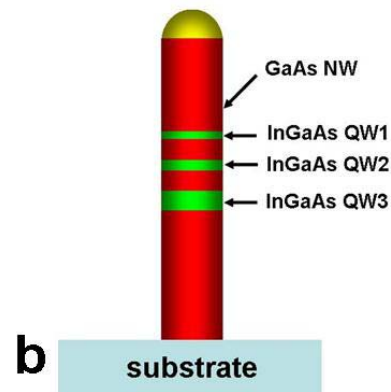
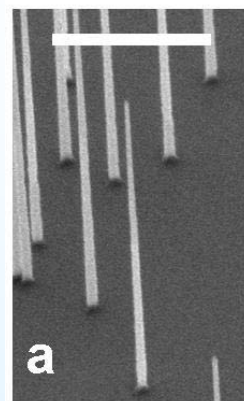


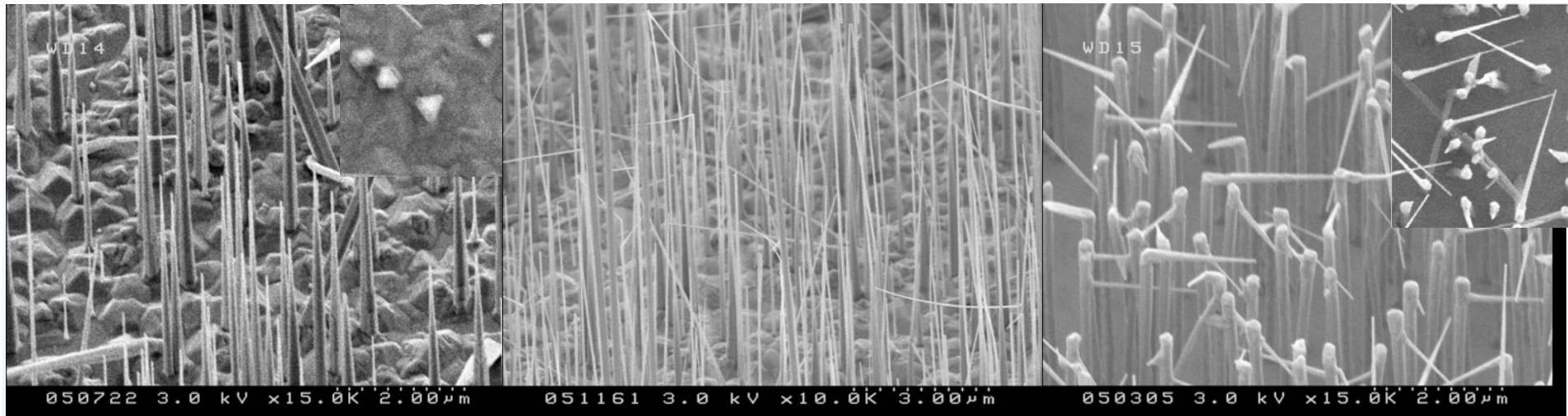
2 μm



Y. Kim, H. Joyce, Q. Gao, H.H. Tan, C. Jagadish, M. Paladugu,
J. Zou, A. Suvorova, *Nano Lett.* 6, 599-604 (2006)

Heterostructural Nanowires on GaAs (111)

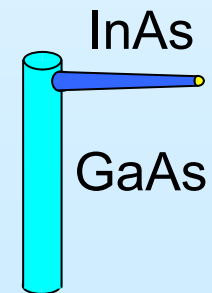
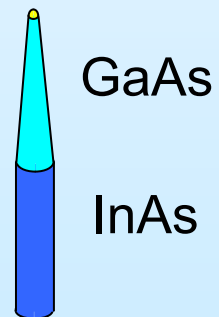




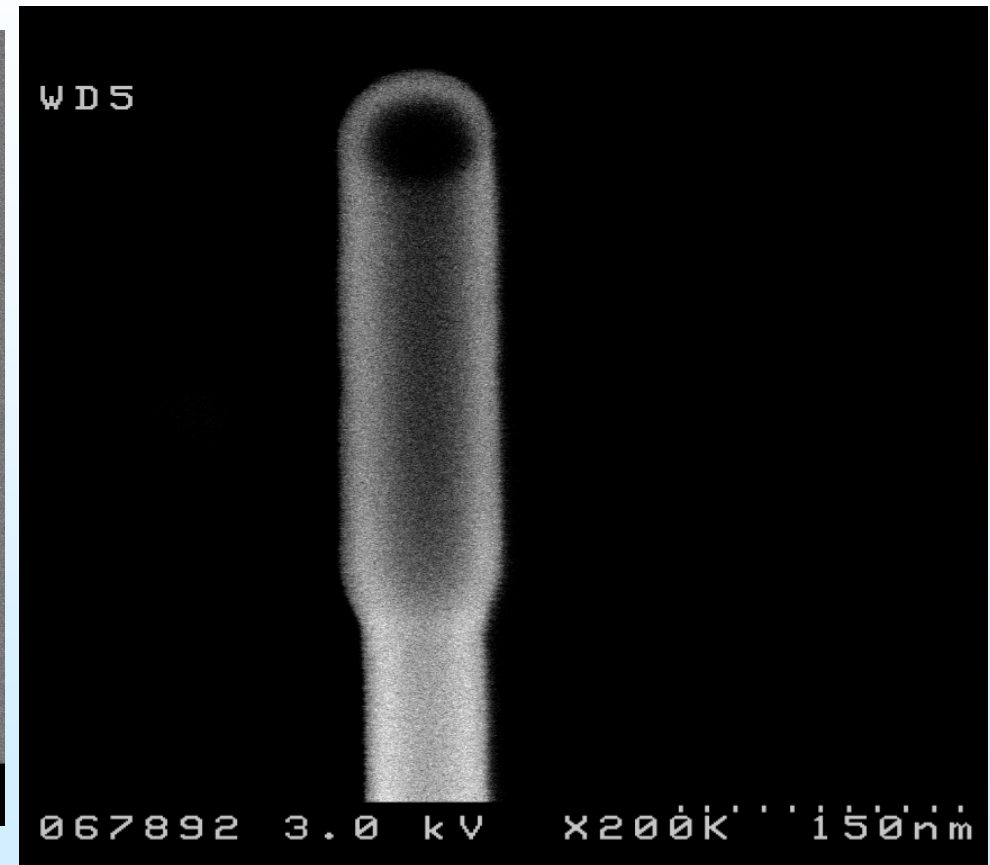
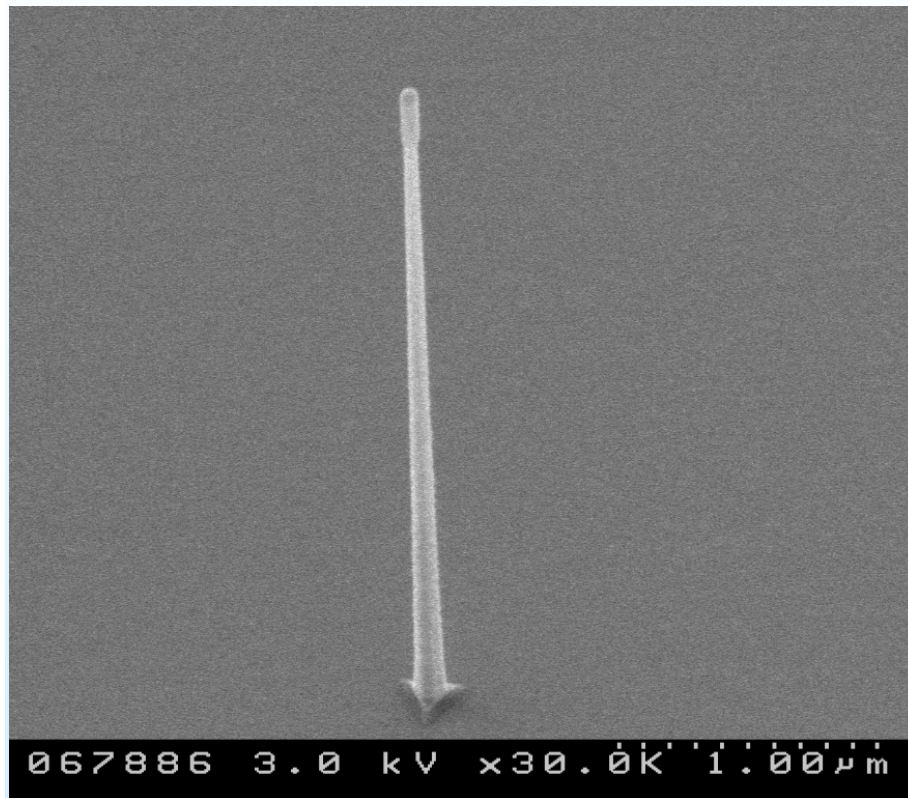
InAs NWs on GaAs sub

GaAs/InAs NW

InAs/GaAs NW



GaSb nanowires on GaAs (111)

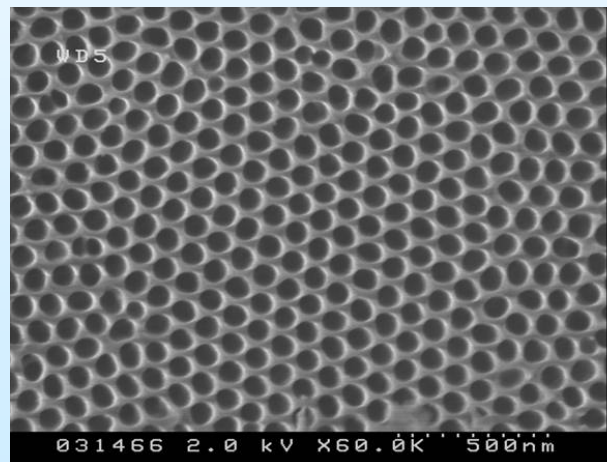
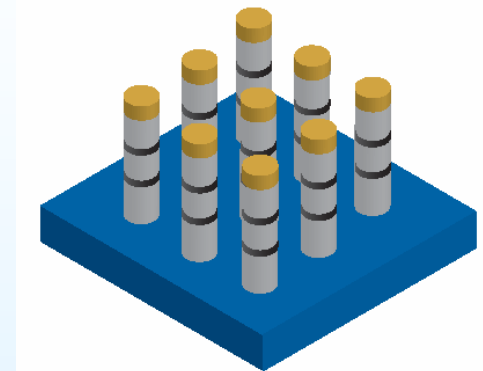
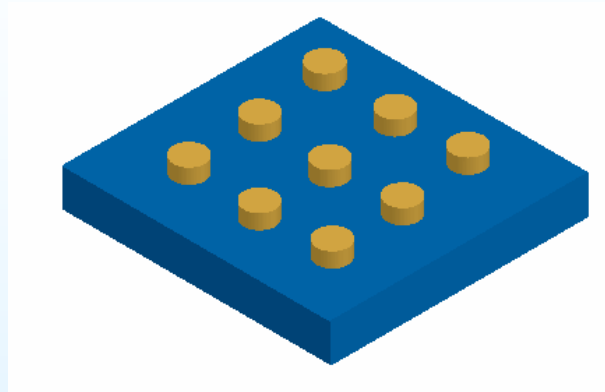
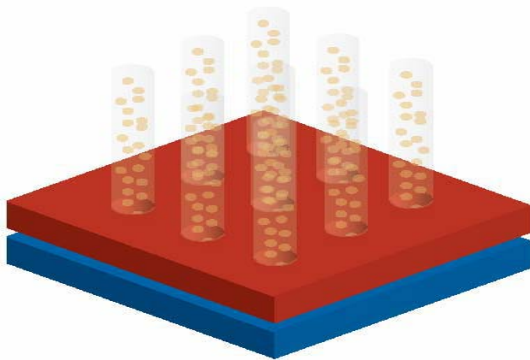


HRTEM of GaSb/GaAs NWs



sharp twin boundary

Future: Ordered Nanowires



Porous Alumina Template

Summary

- **Quantum Dots - strongly affected by growth conditions**
- **MOCVD growth of Quantum Dots is challenging and promising for optoelectronic device applications**
- **Quantum Well and Quantum Dot Intermixing Techniques are promising for Optoelectronic Device Integration**
- **Understanding defect generation, diffusion and annihilation processes are important for achieving QWI and QDI**
- **Carrier lifetime**
- **Nanowires offer opportunities to develop novel nano-photonic devices, e.g. single photon sources, QD lattices, photonic crystals**

Acknowledgment

- Kallista Stewart, Sudha Mokkapati, Satya Barik, Greg Jolley, Victoria Coleman, Michael Fraser, Paulus Gareso, Mykhaylo Lysevytch, Ian McKerracher, Hannah Joyce, Mohan Paladugu (UQ)
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- Mike Gal, University of New South Wales
- Matthew Phillips, University of Technology, Sydney
- Zou Jin, University of Queensland
- A. Suvorova, University of Western Australia

Australian Research Council

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Thank you for your attention